

FIG.1

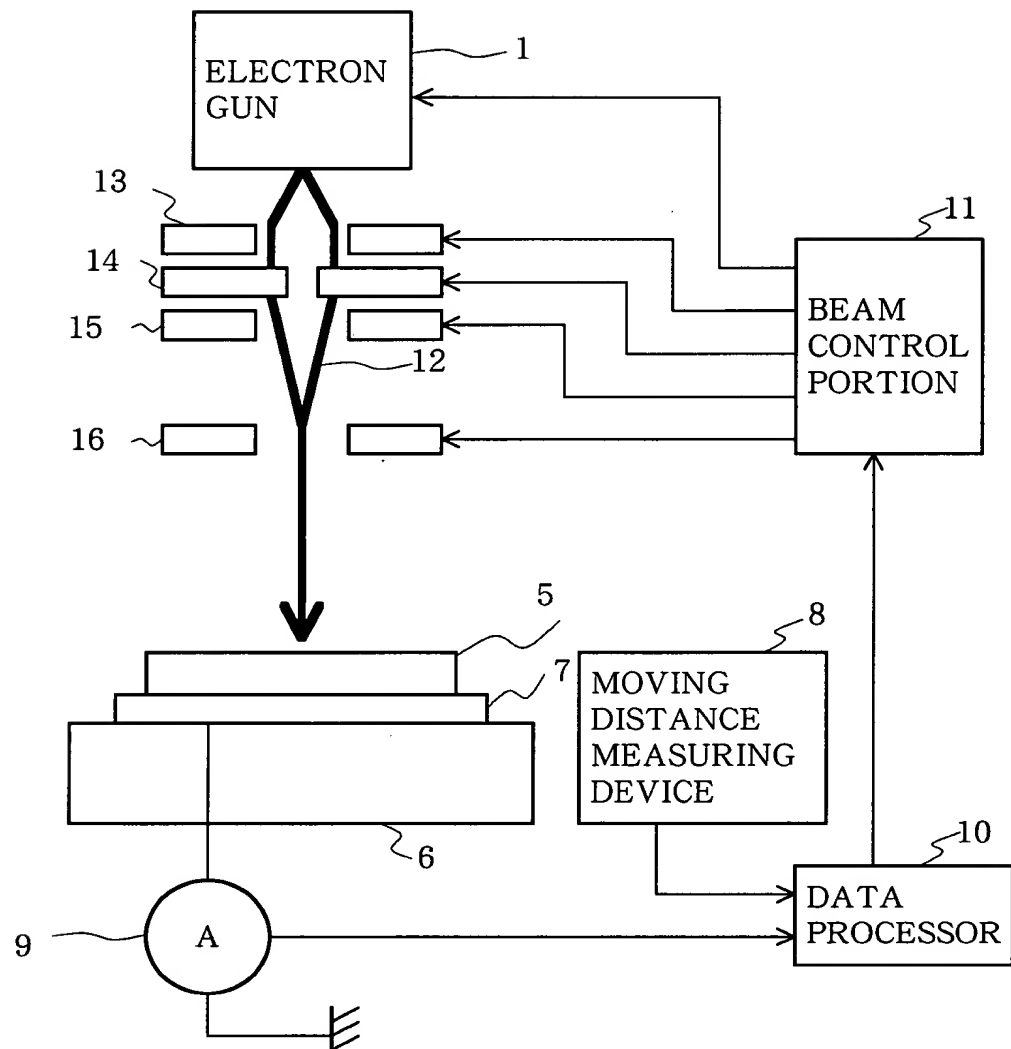


FIG.2

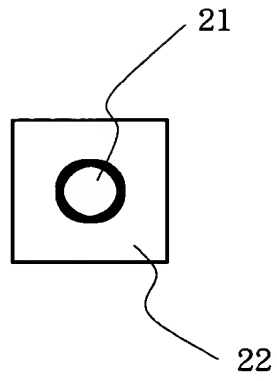


FIG. 3a

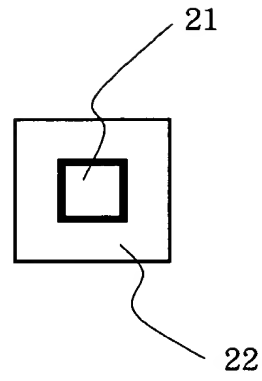


FIG. 3b

FIG. 3a is a schematic diagram of a square frame 22 containing a circular element 21. FIG. 3b is a schematic diagram of a square frame 22 containing a square element 21.

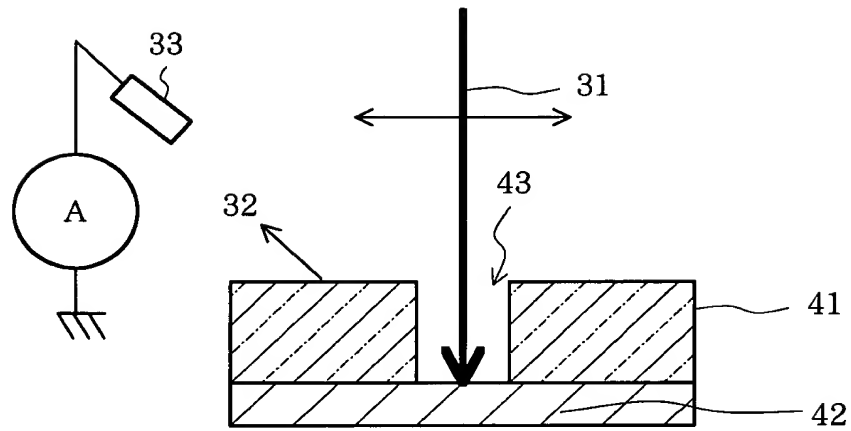
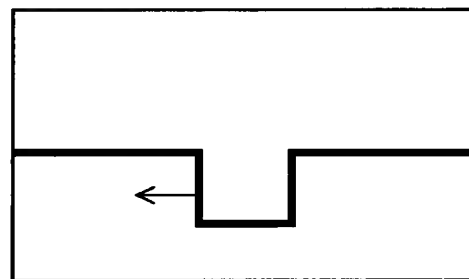


FIG.4a

AMOUNT OF  
SECONDARY ELECTRON



POSITION

FIG.4b

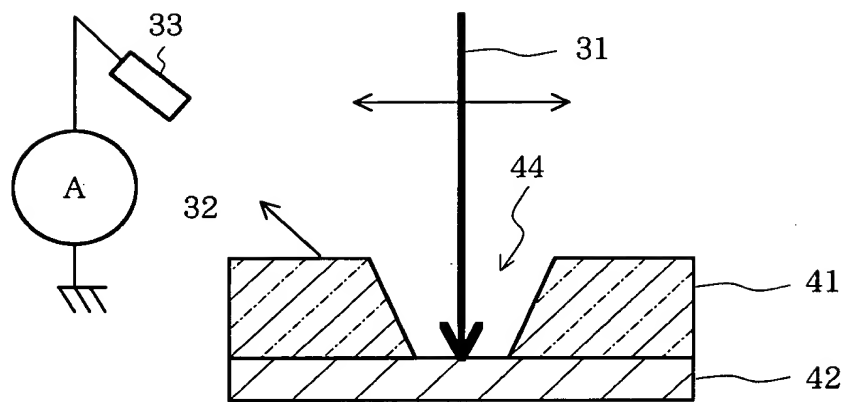
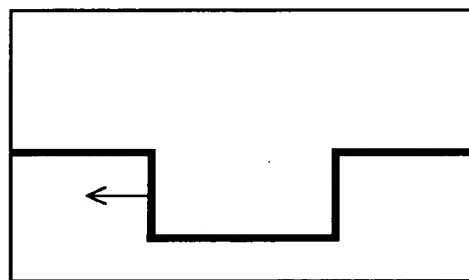


FIG.5a

AMOUNT OF  
SECONDARY ELECTRON



POSITION

FIG.5b

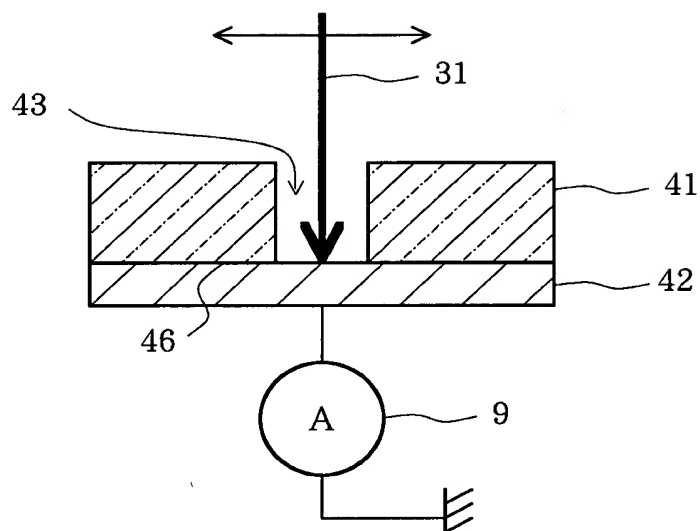


FIG.6a

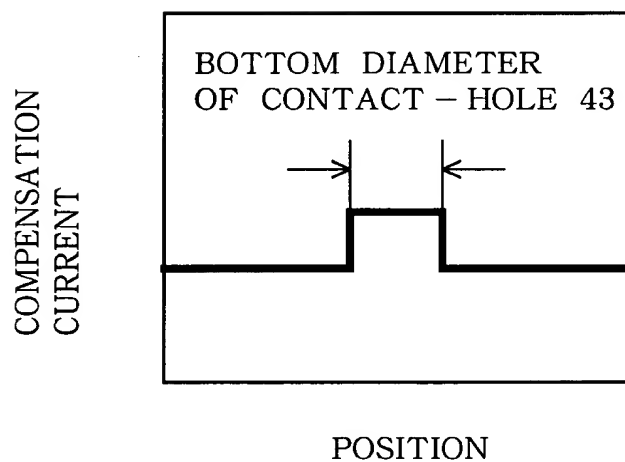


FIG.6b

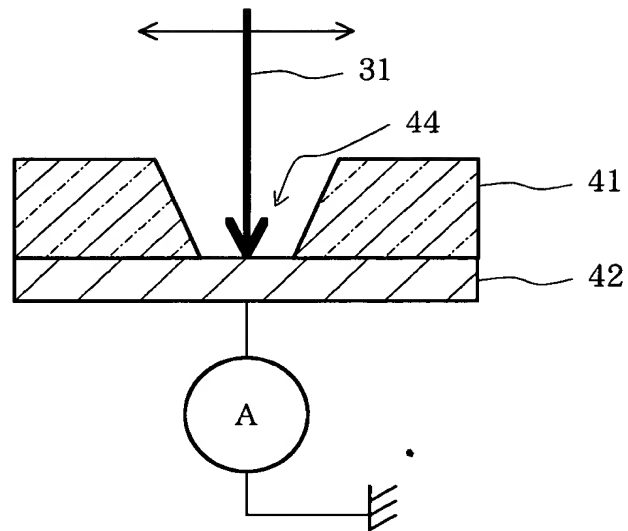
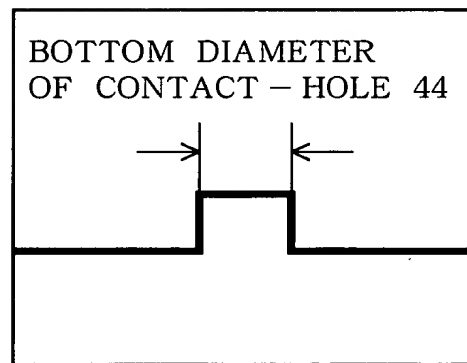


FIG.7a

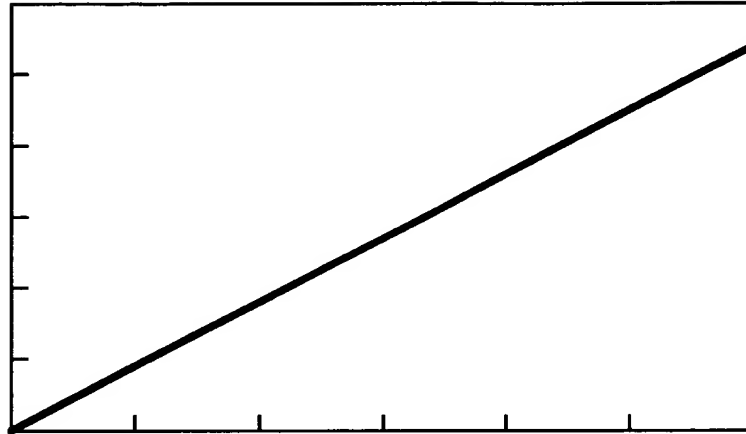
COMPENSATION CURRENT



POSITION

FIG.7b

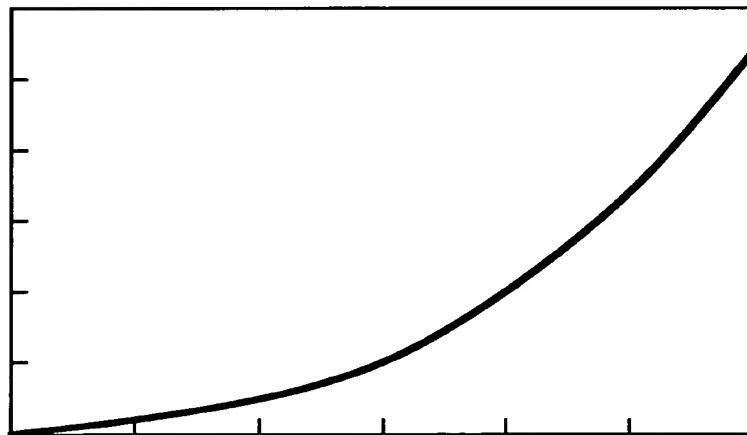
COMPENSATION CURRENT



BOTTOM AREA OF A CONTACT - HOLE

FIG.8

COMPENSATION CURRENT



CONVERTED DIAMETER OF A CONTACT - HOLE

FIG.9



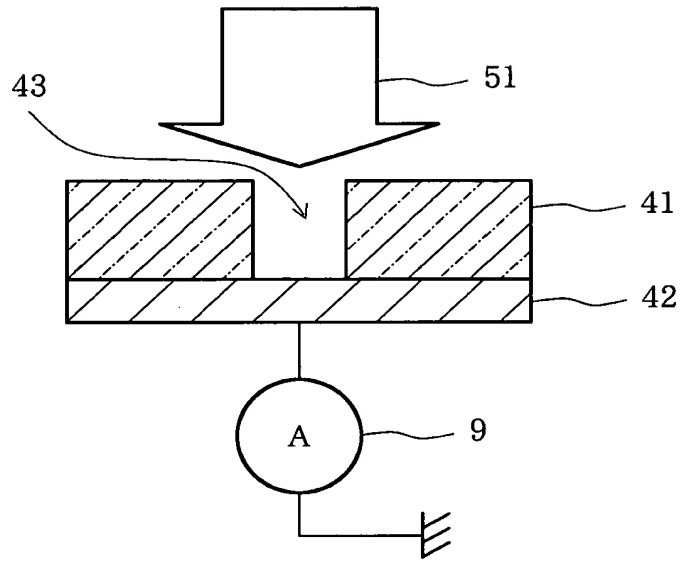
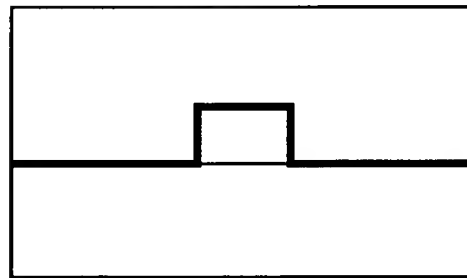


FIG.10a

COMPENSATION CURRENT



POSITION

FIG.10b

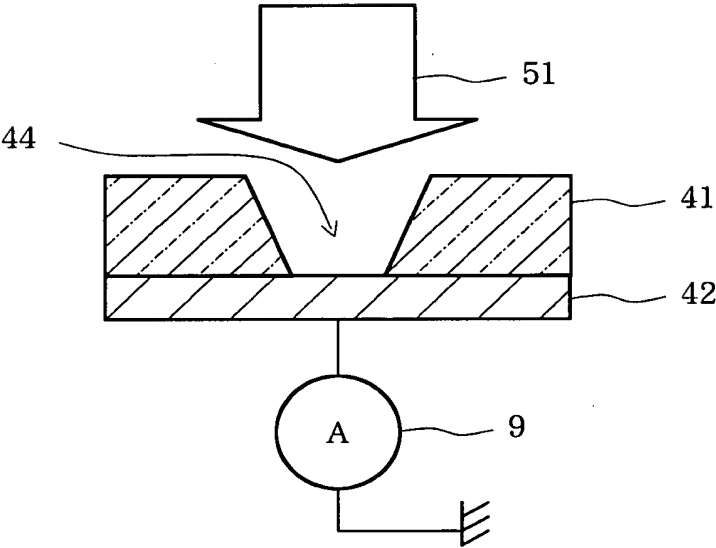
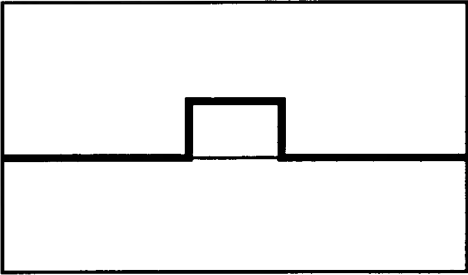


FIG.11a

COMPENSATION CURRENT



POSITION

FIG.11b

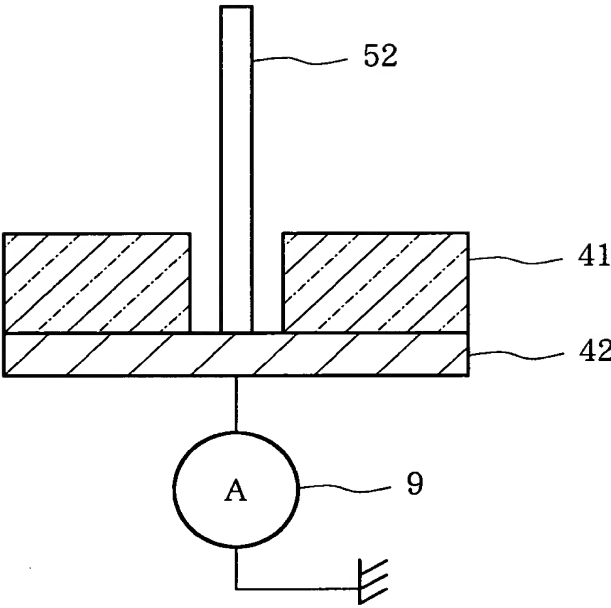


FIG.12a

COMPENSATION CURRENT

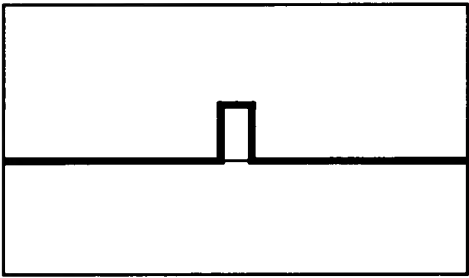


FIG.12b

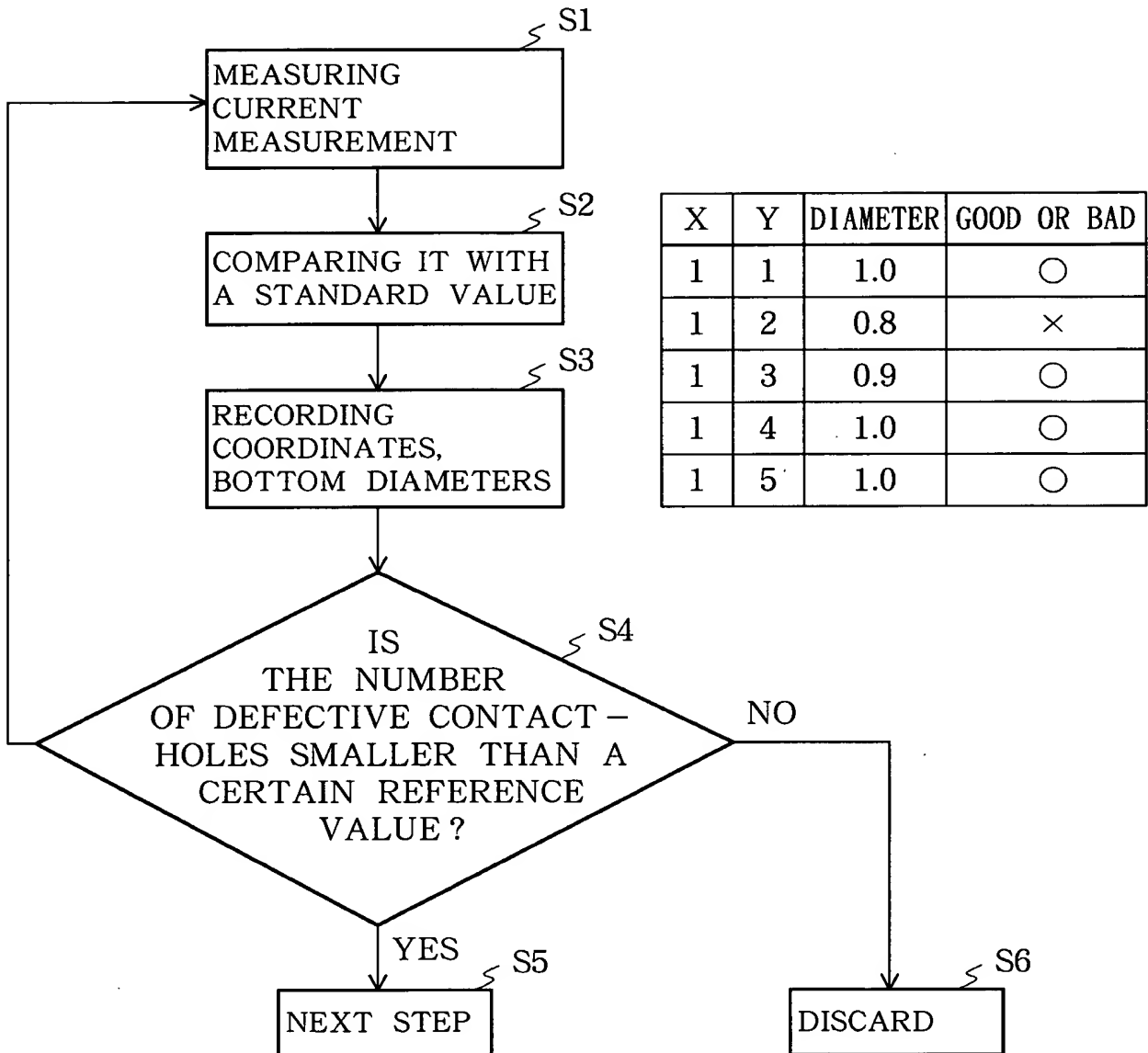


FIG.13

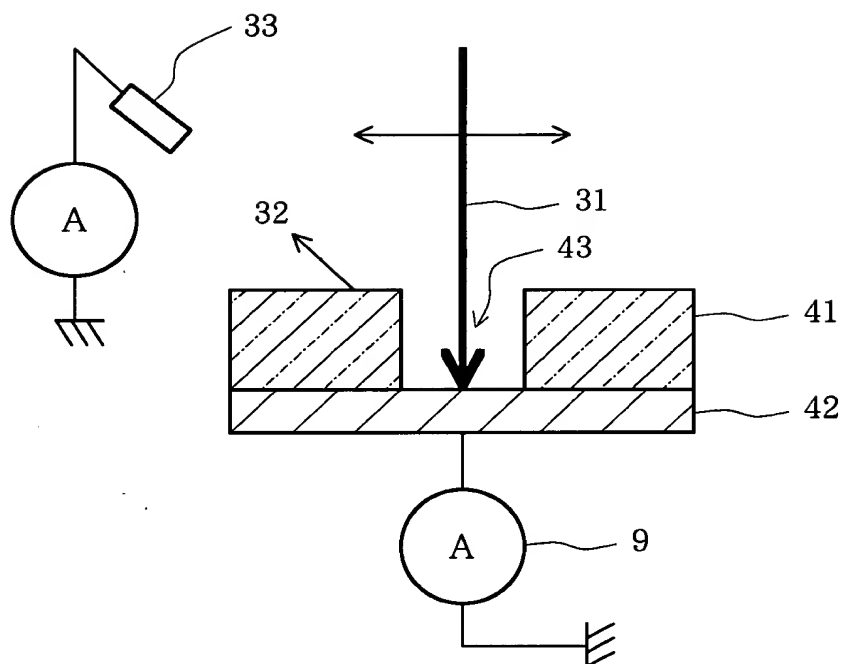
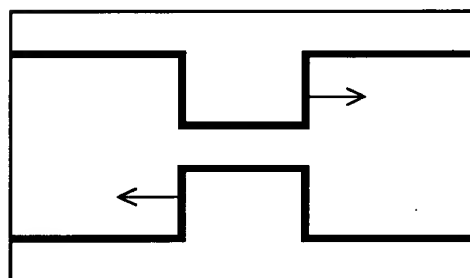


FIG.14a

COMPENSATION CURRENT



POSITION

FIG.14b

AMOUNT OF SECONDARY CURRENT

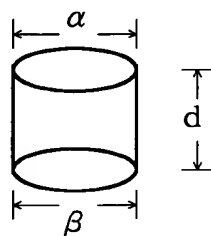


FIG.14c

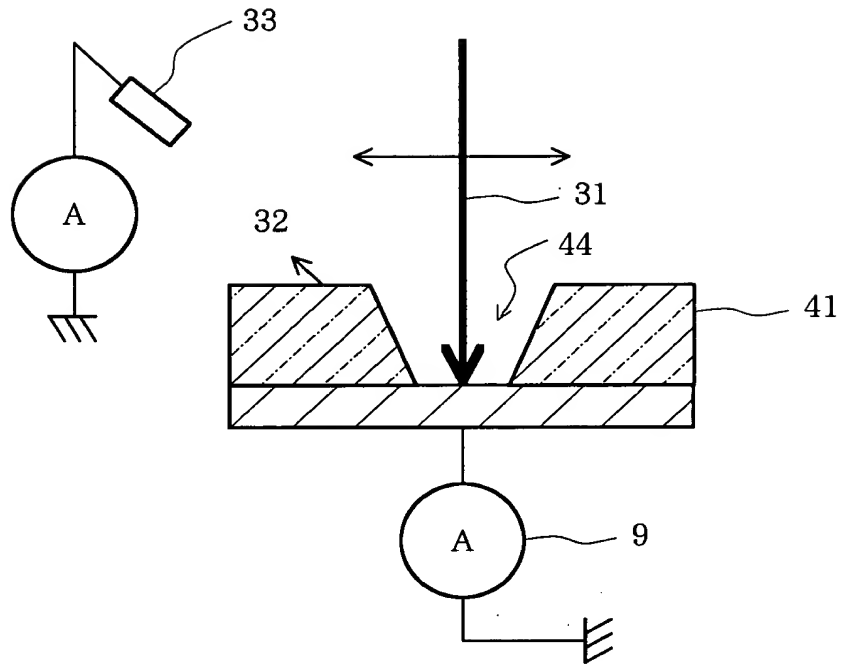
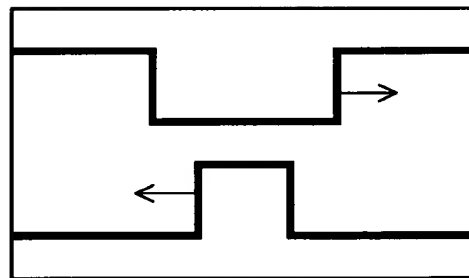


FIG.15a

COMPENSATION CURRENT



POSITION

FIG.15b

AMOUNT OF SECONDARY CURRENT

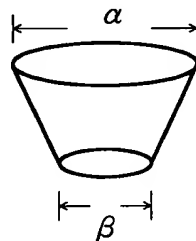


FIG.15c

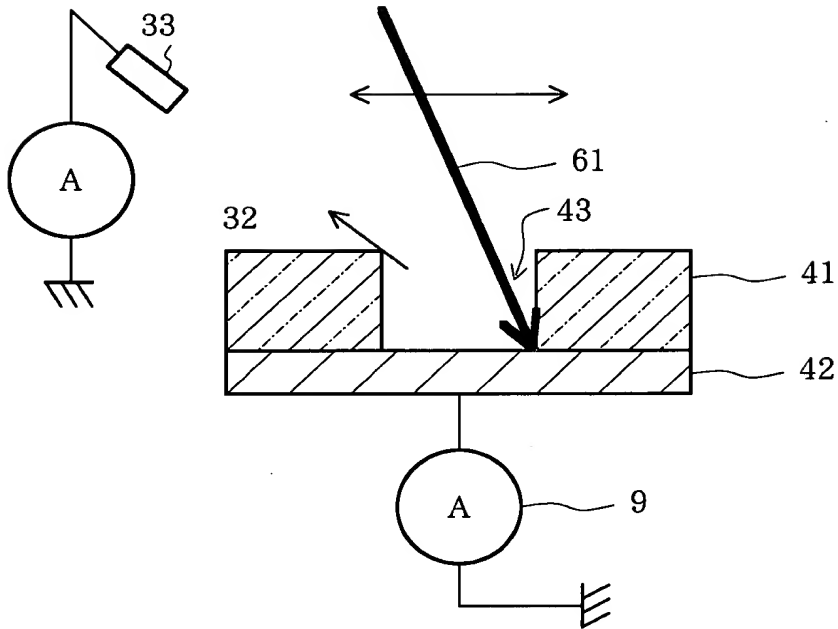


FIG.16a

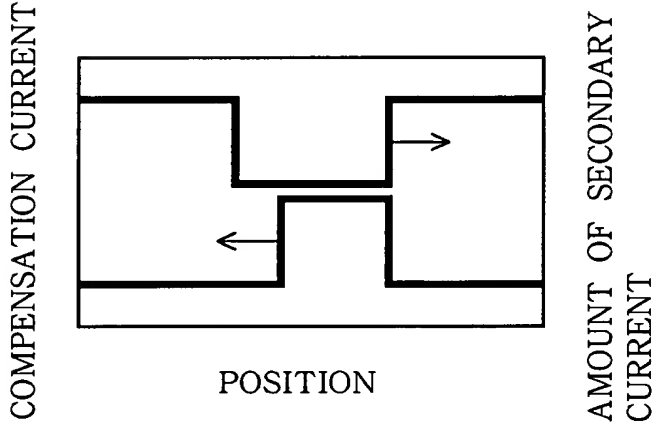


FIG.16b

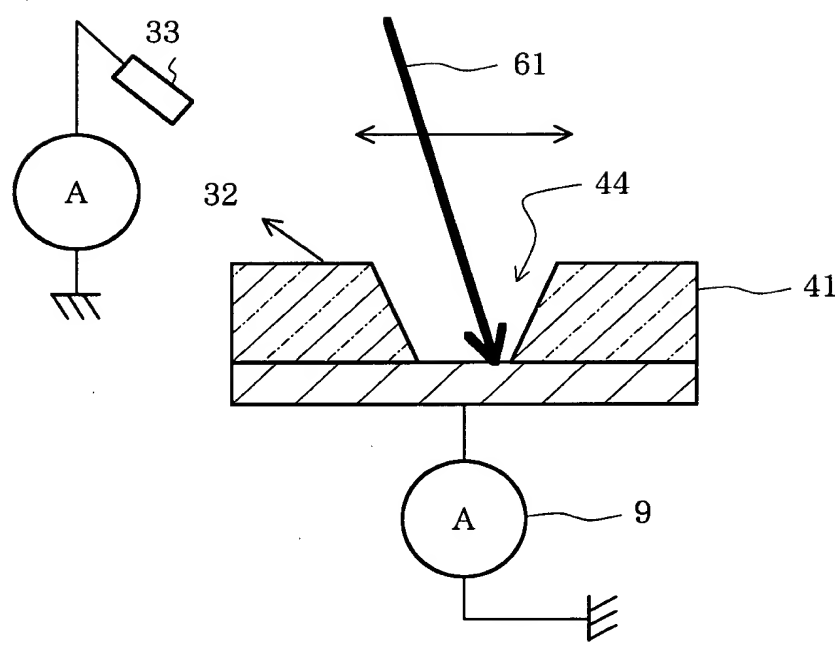


FIG.17a

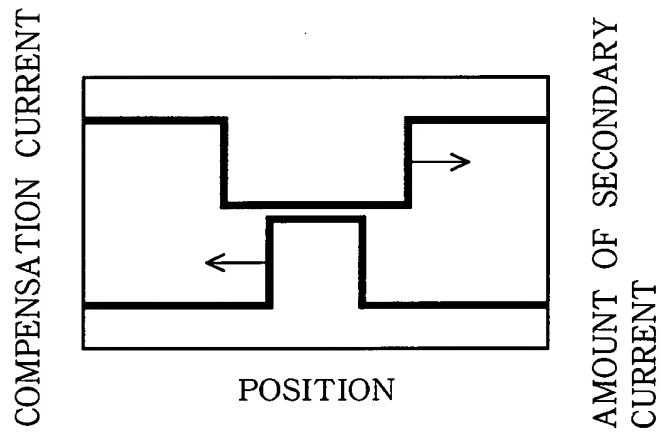


FIG.17b



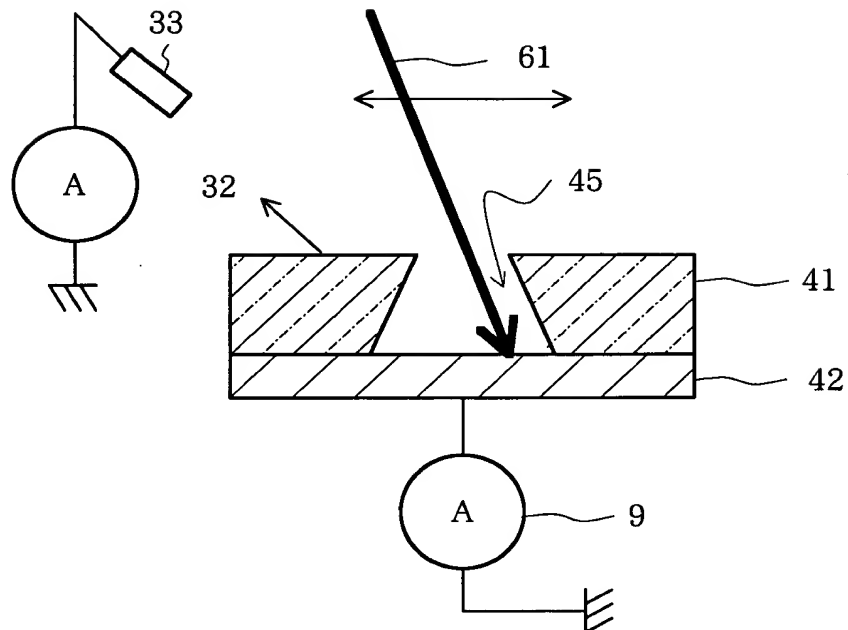


FIG.18a

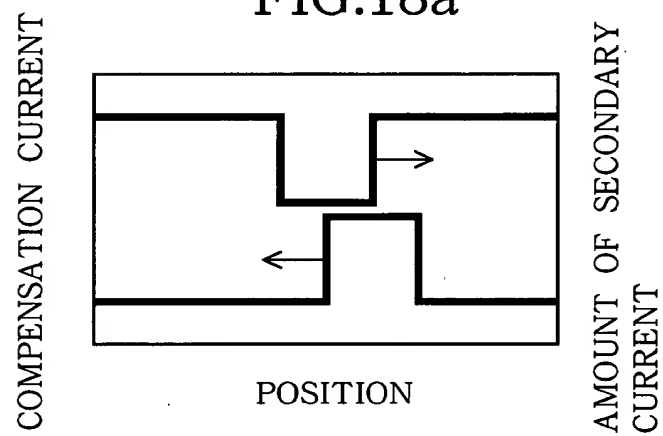


FIG.18b



FIG.18c

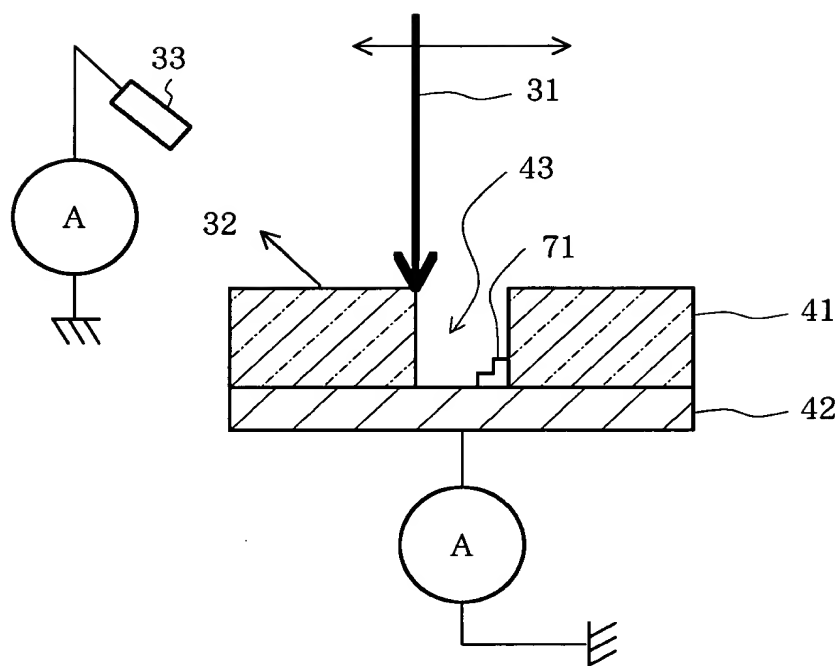


FIG.19a

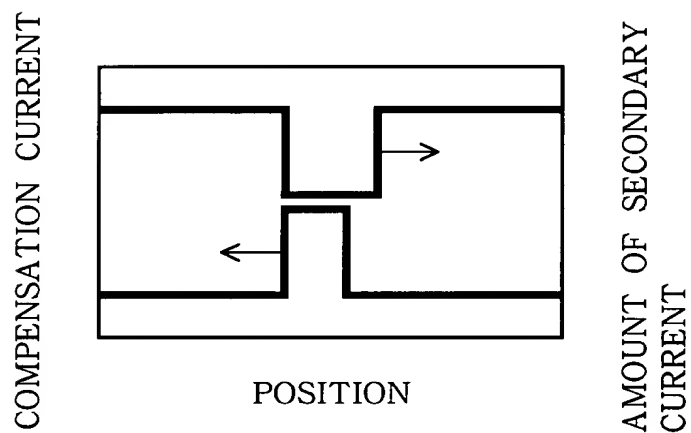


FIG.19b

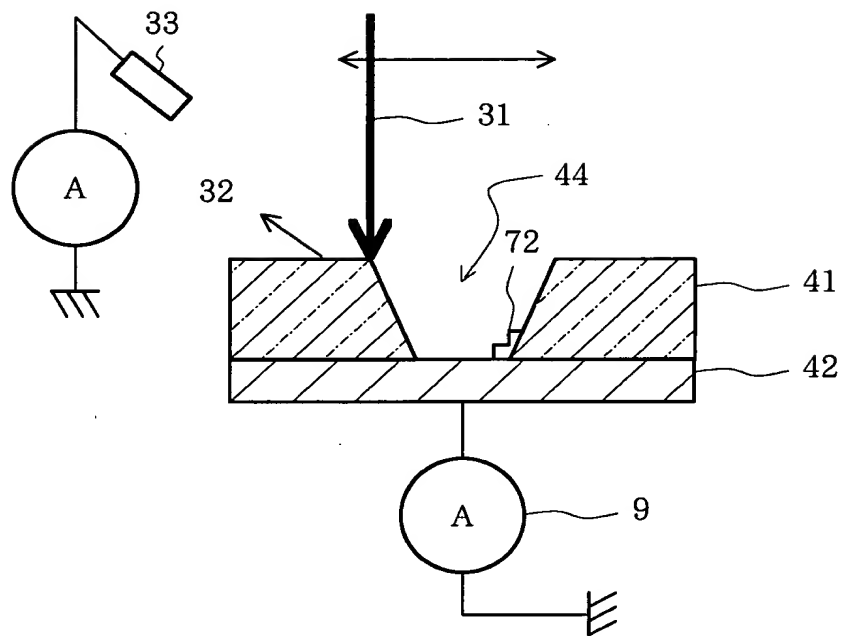


FIG. 20a

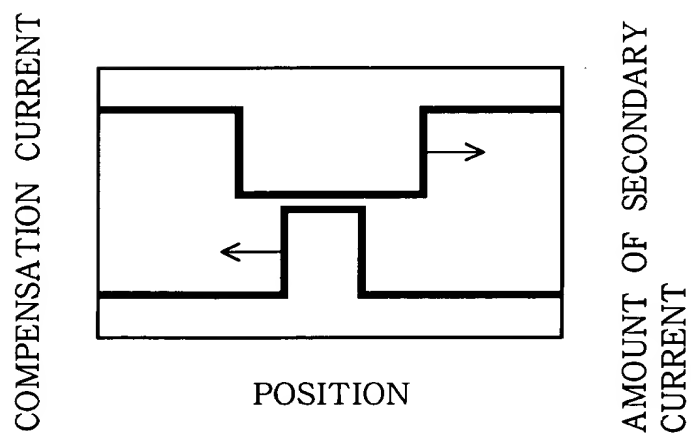


FIG. 20b

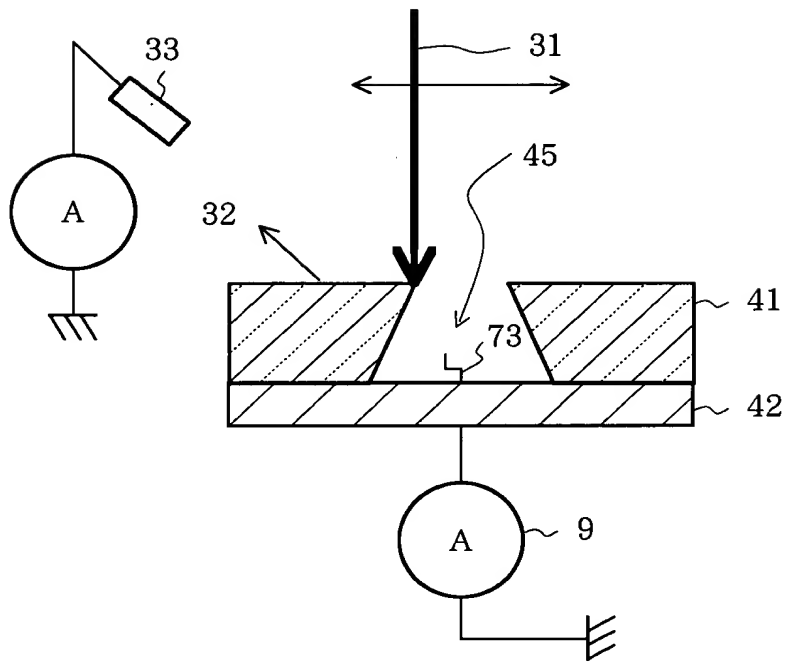


FIG.21a

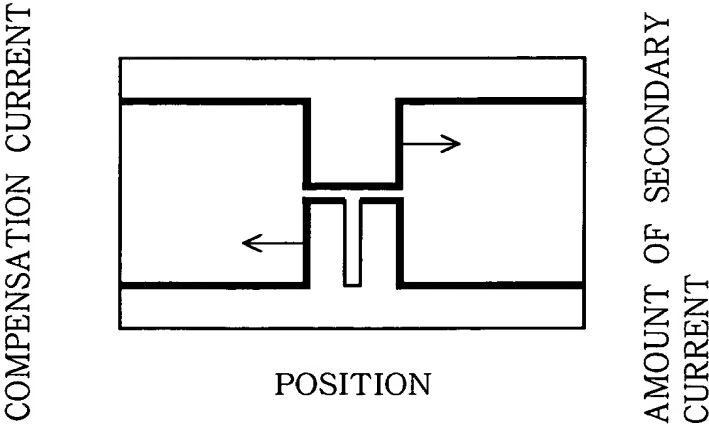


FIG.21b

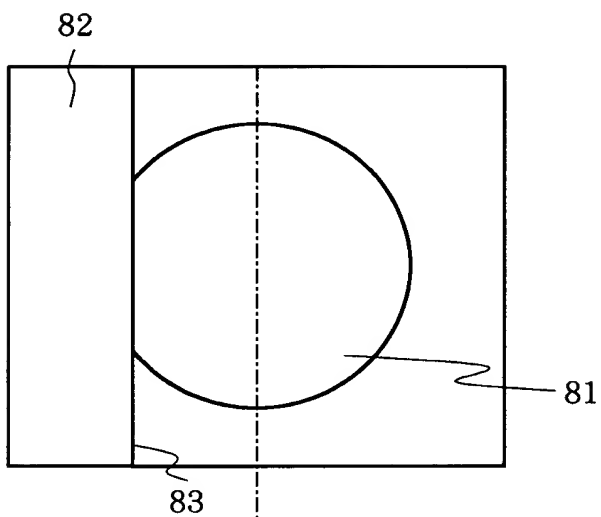


FIG.22a

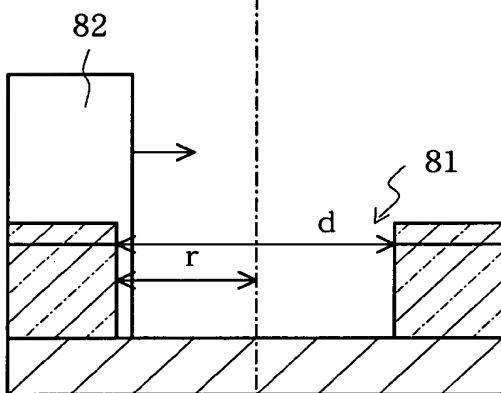


FIG.22b

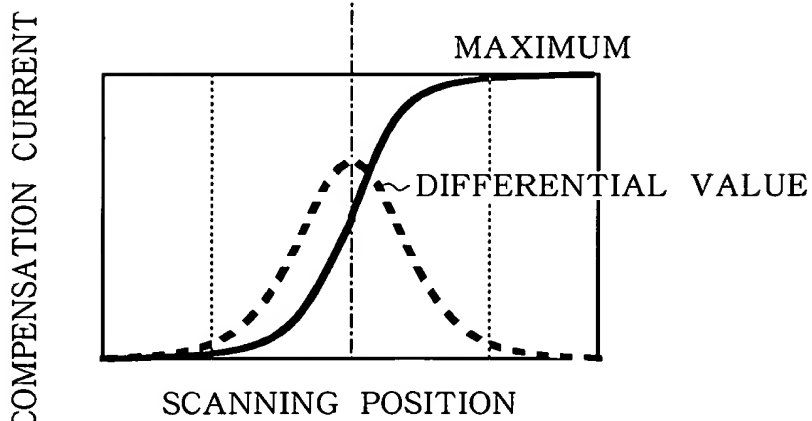


FIG.22c

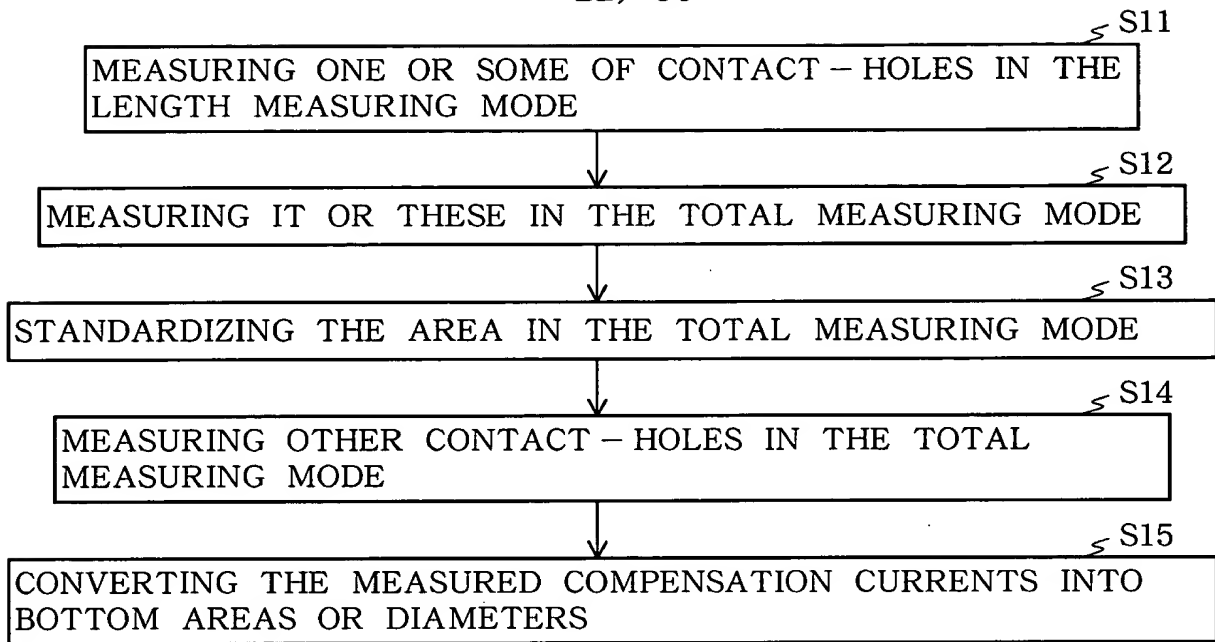


FIG.23

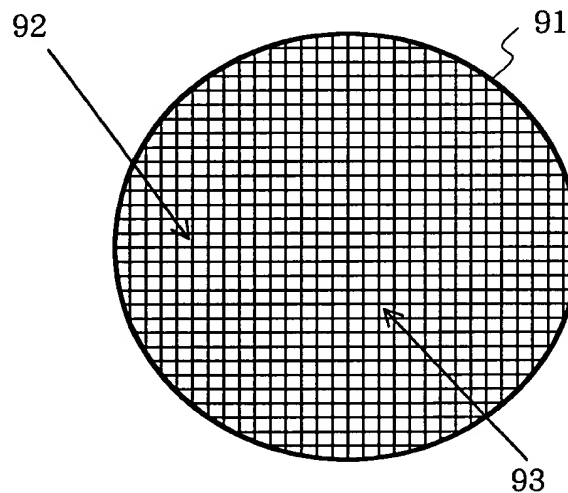


FIG.24

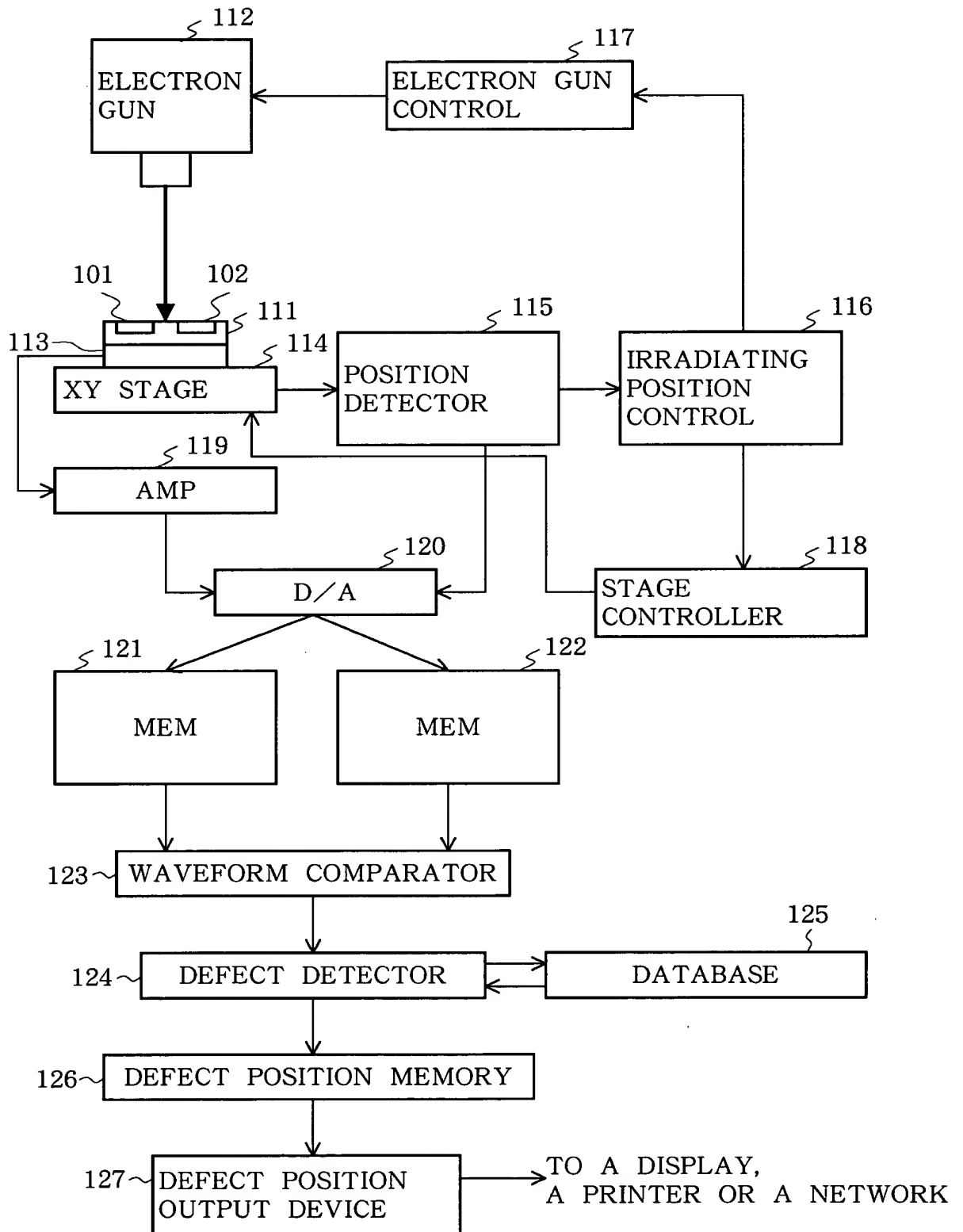


FIG.25

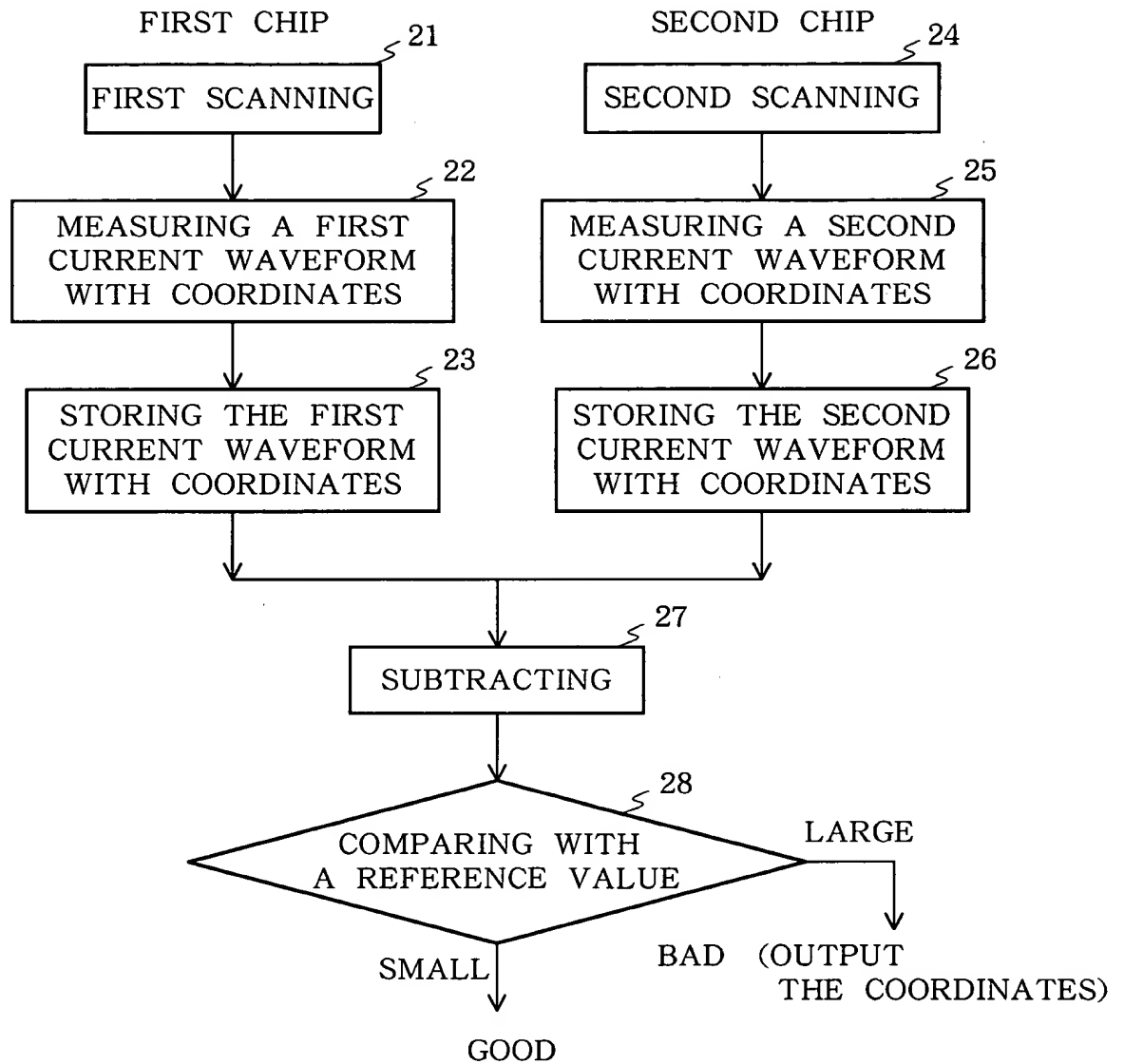


FIG.26



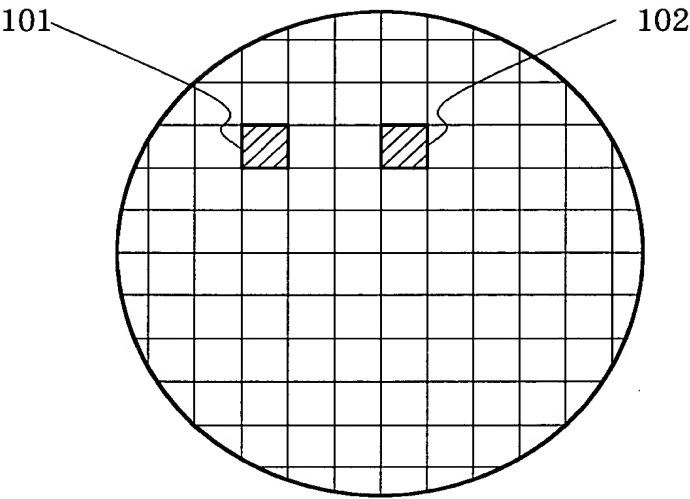


FIG. 27

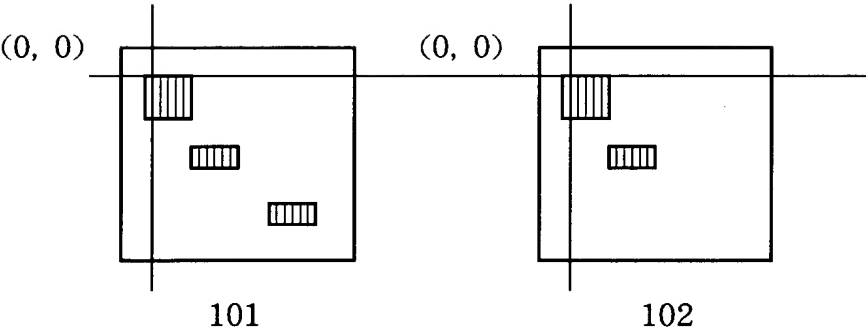


FIG. 28

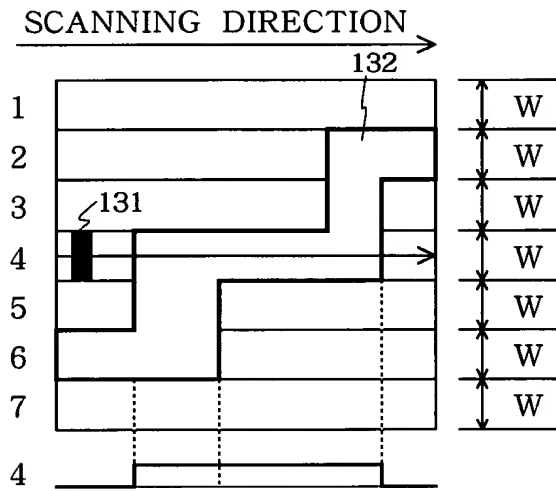


FIG. 29a

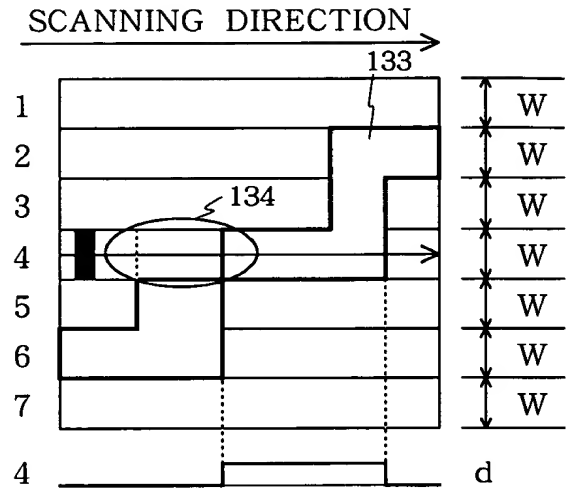


FIG. 29b

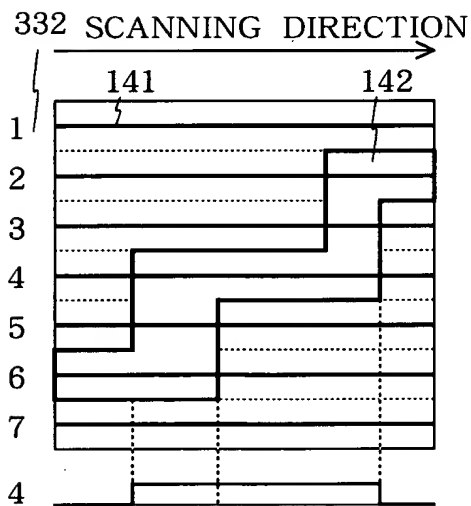


FIG. 30a

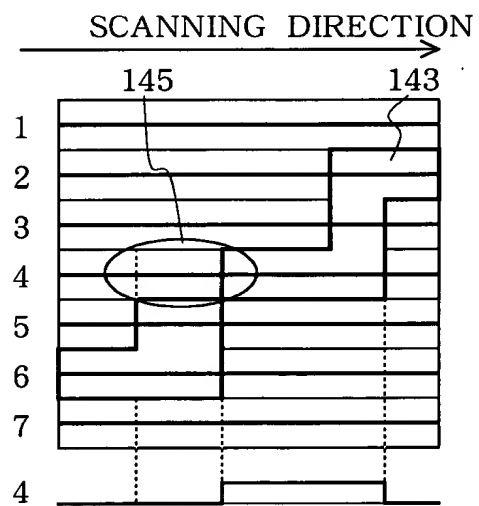


FIG. 30b

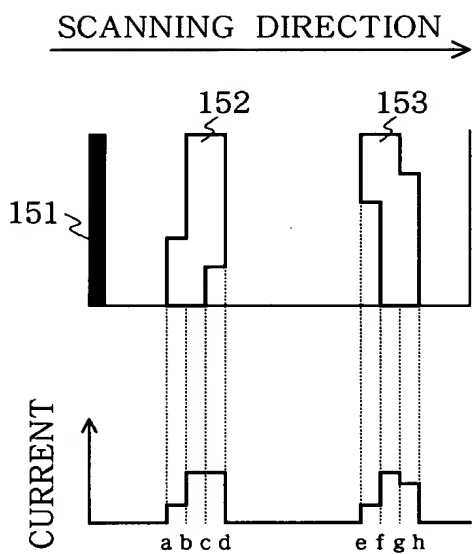


FIG.31a

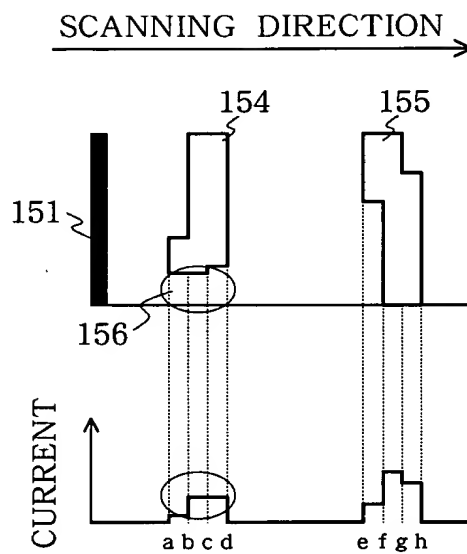


FIG.31b

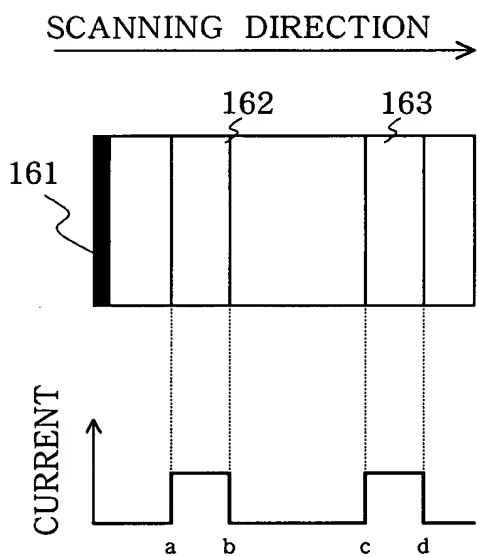


FIG.32a

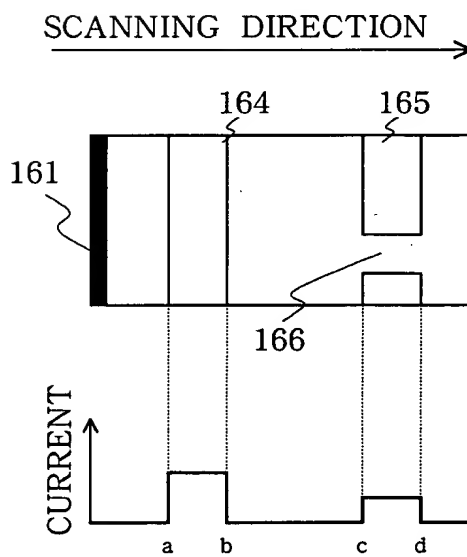


FIG.32b

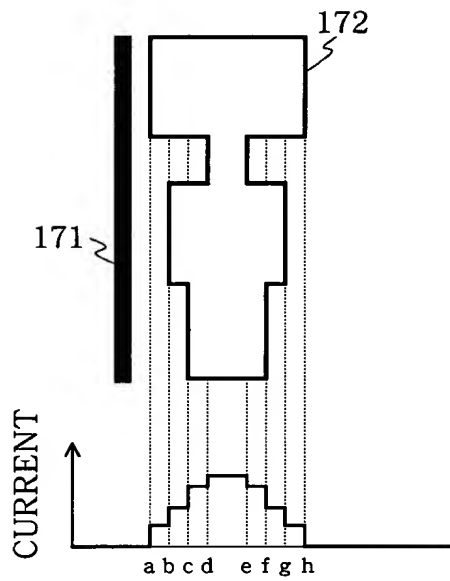


FIG. 33a

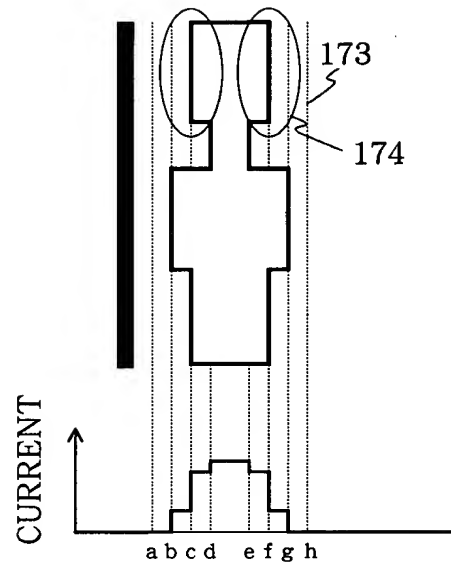


FIG. 33b

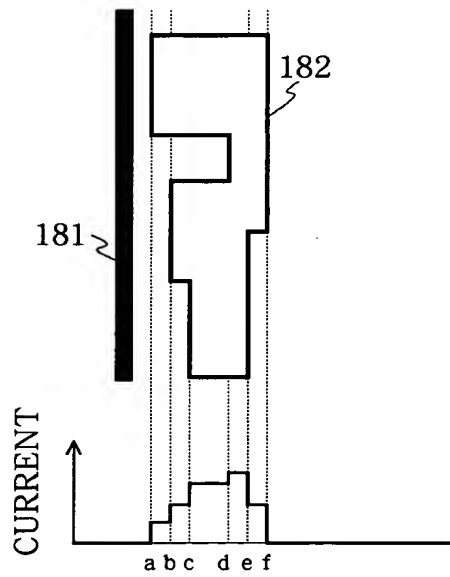


FIG. 34a

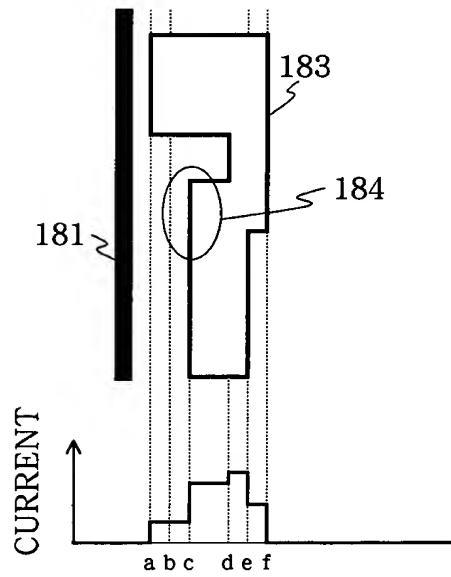


FIG. 34b

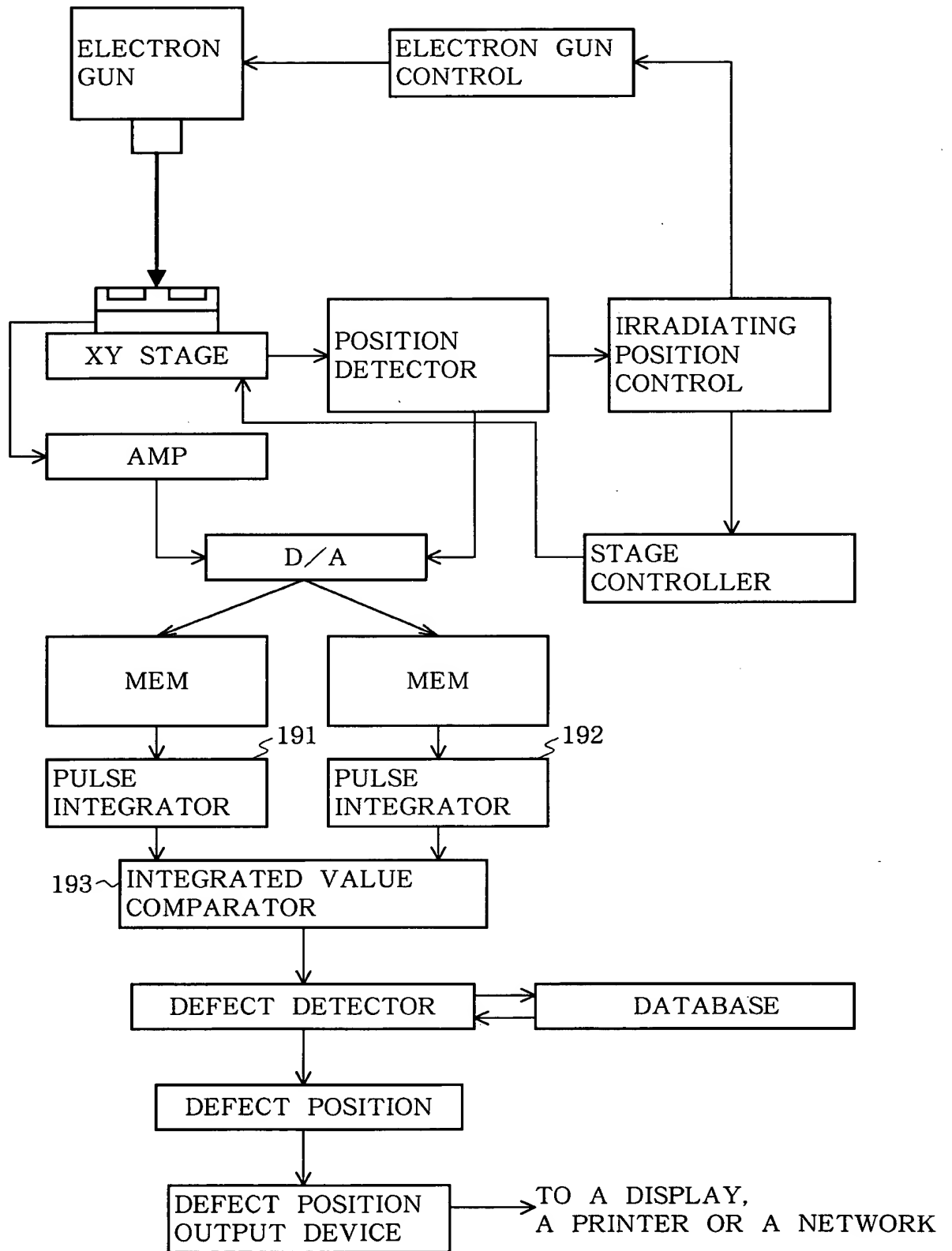


FIG.35

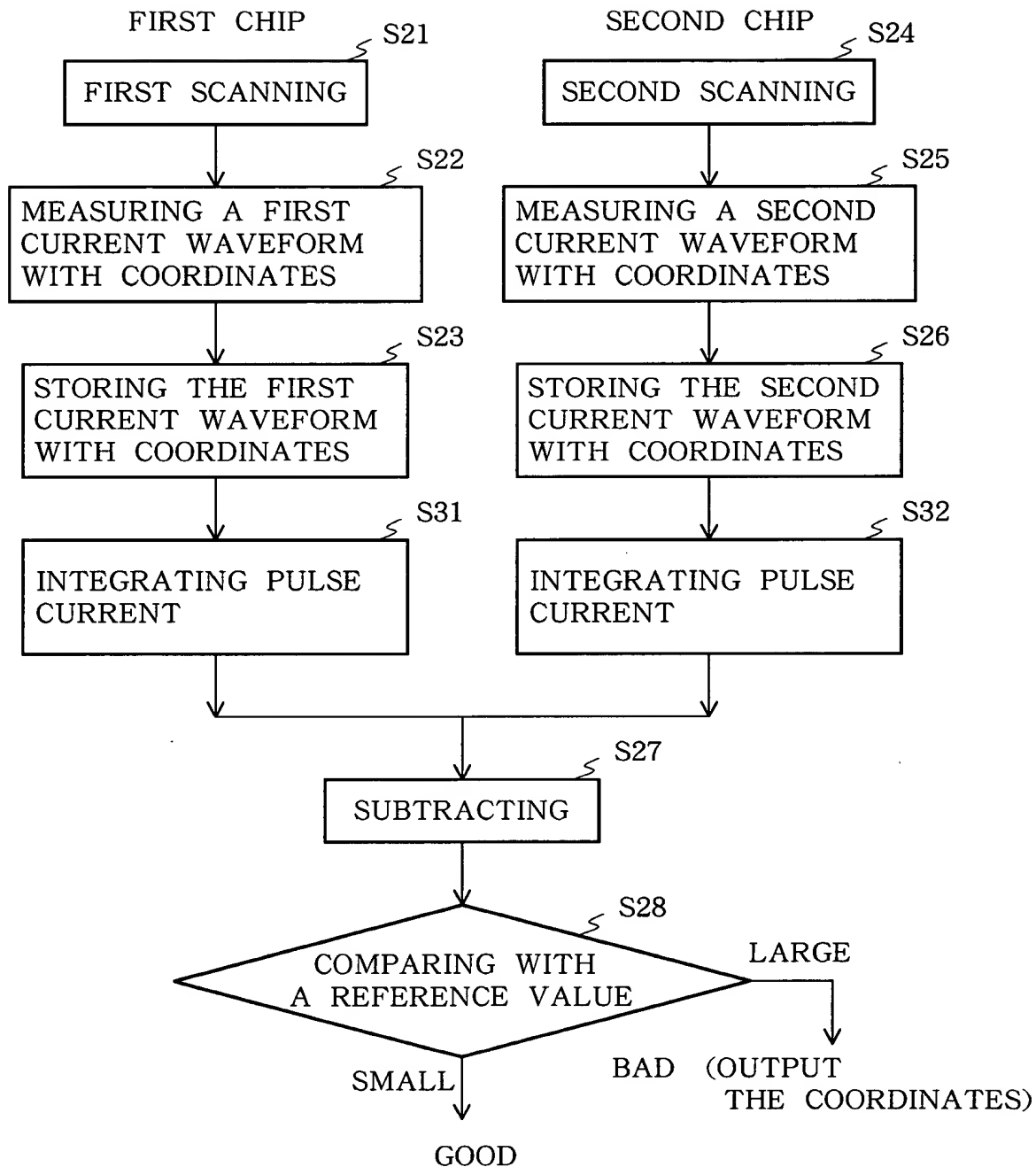


FIG.36

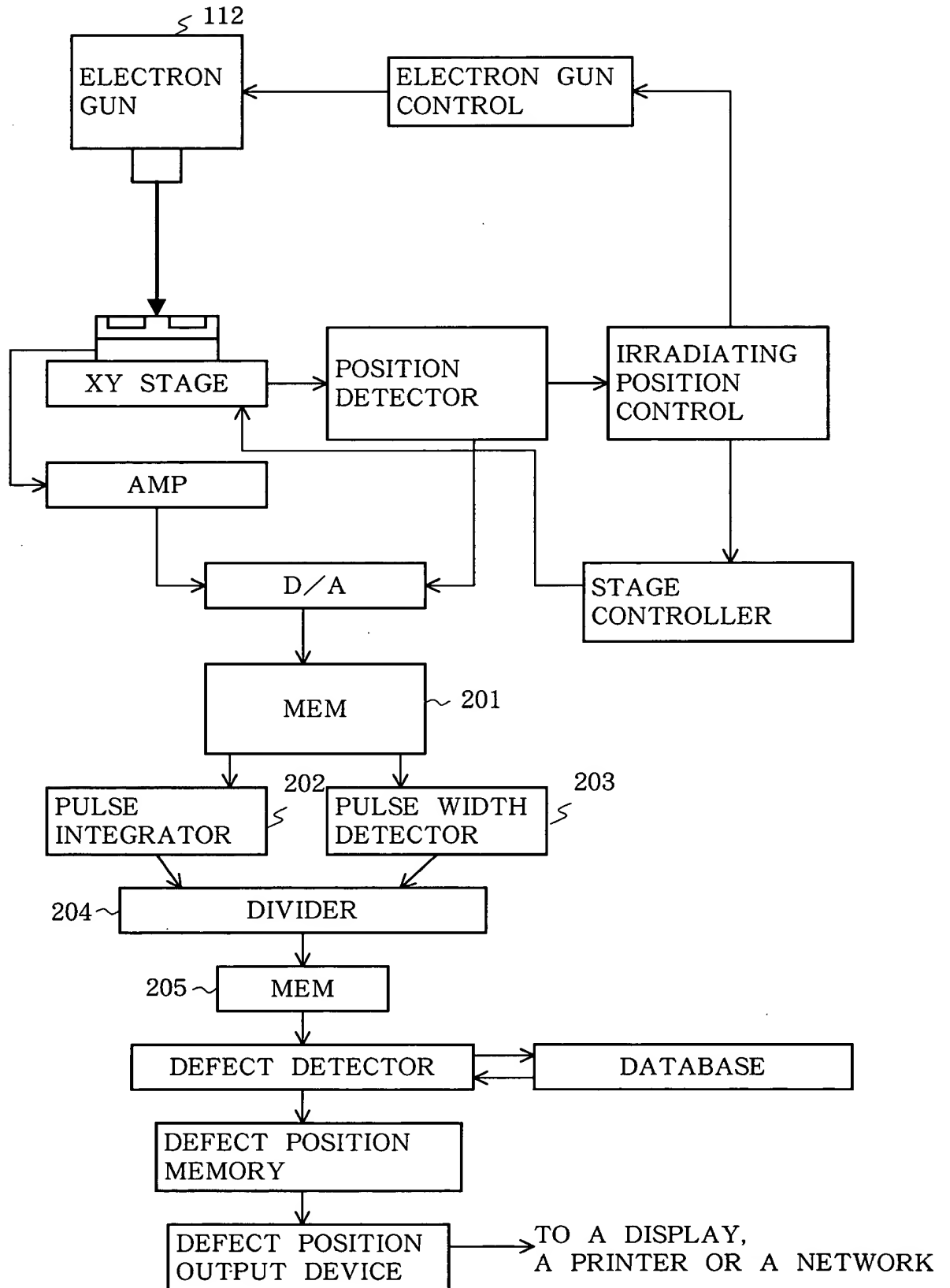


FIG.37

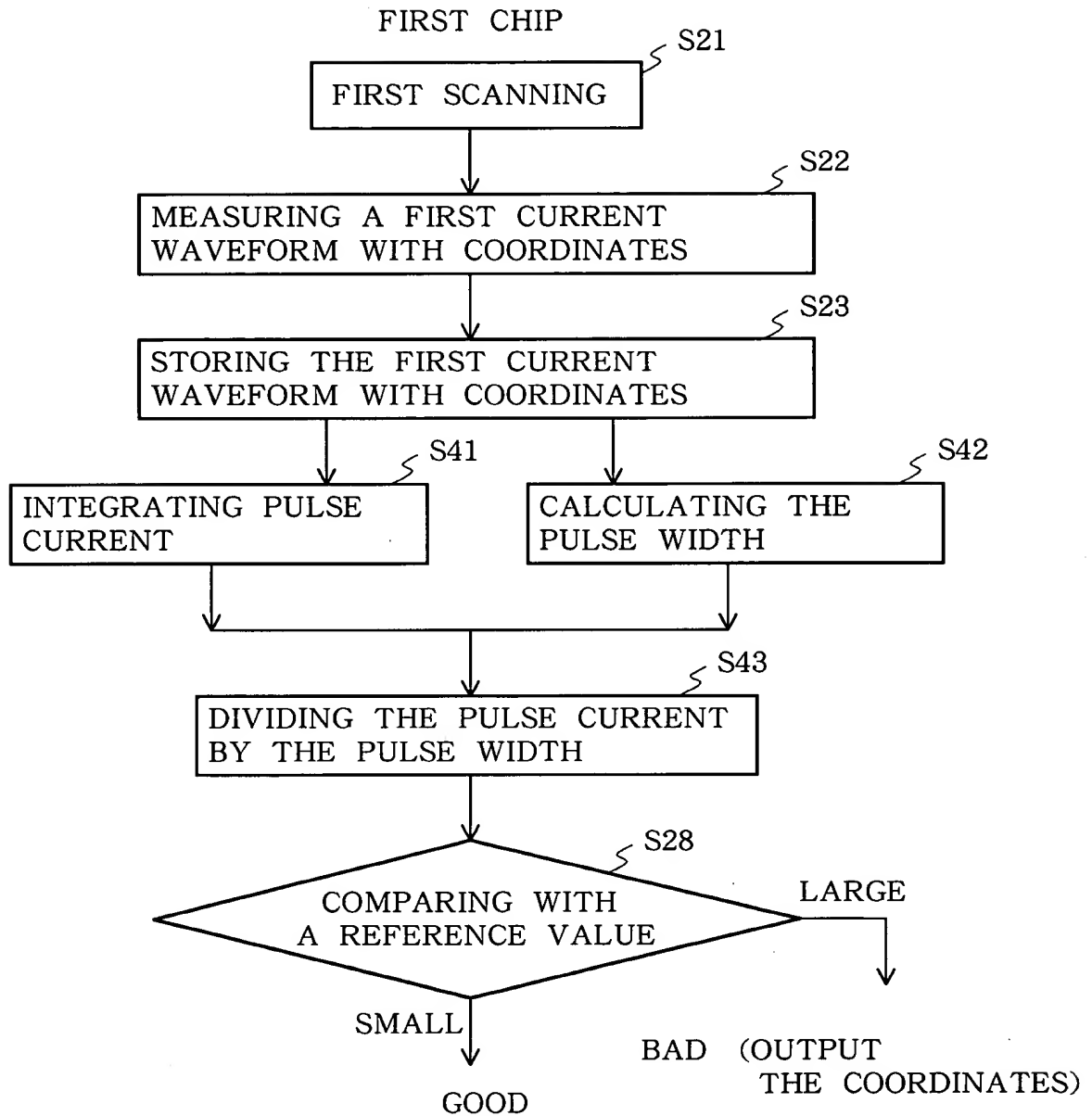


FIG.38



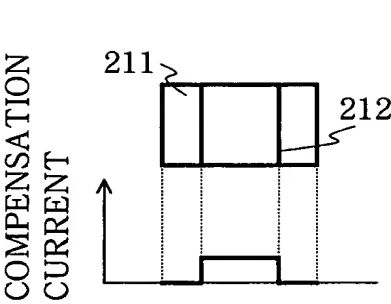


FIG.39a

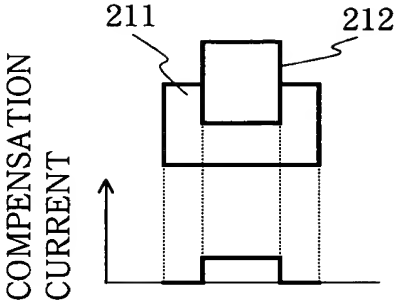
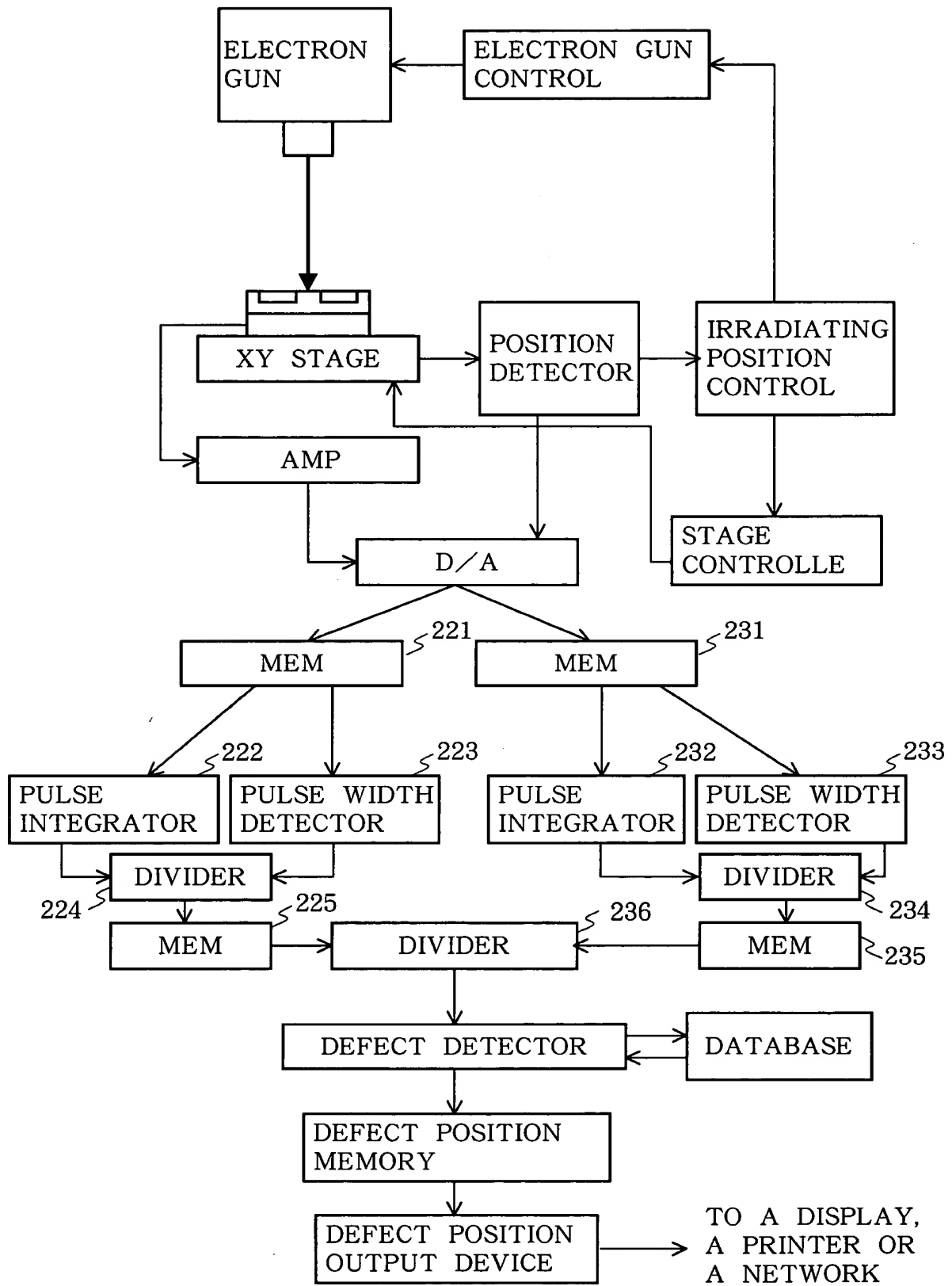


FIG.39b



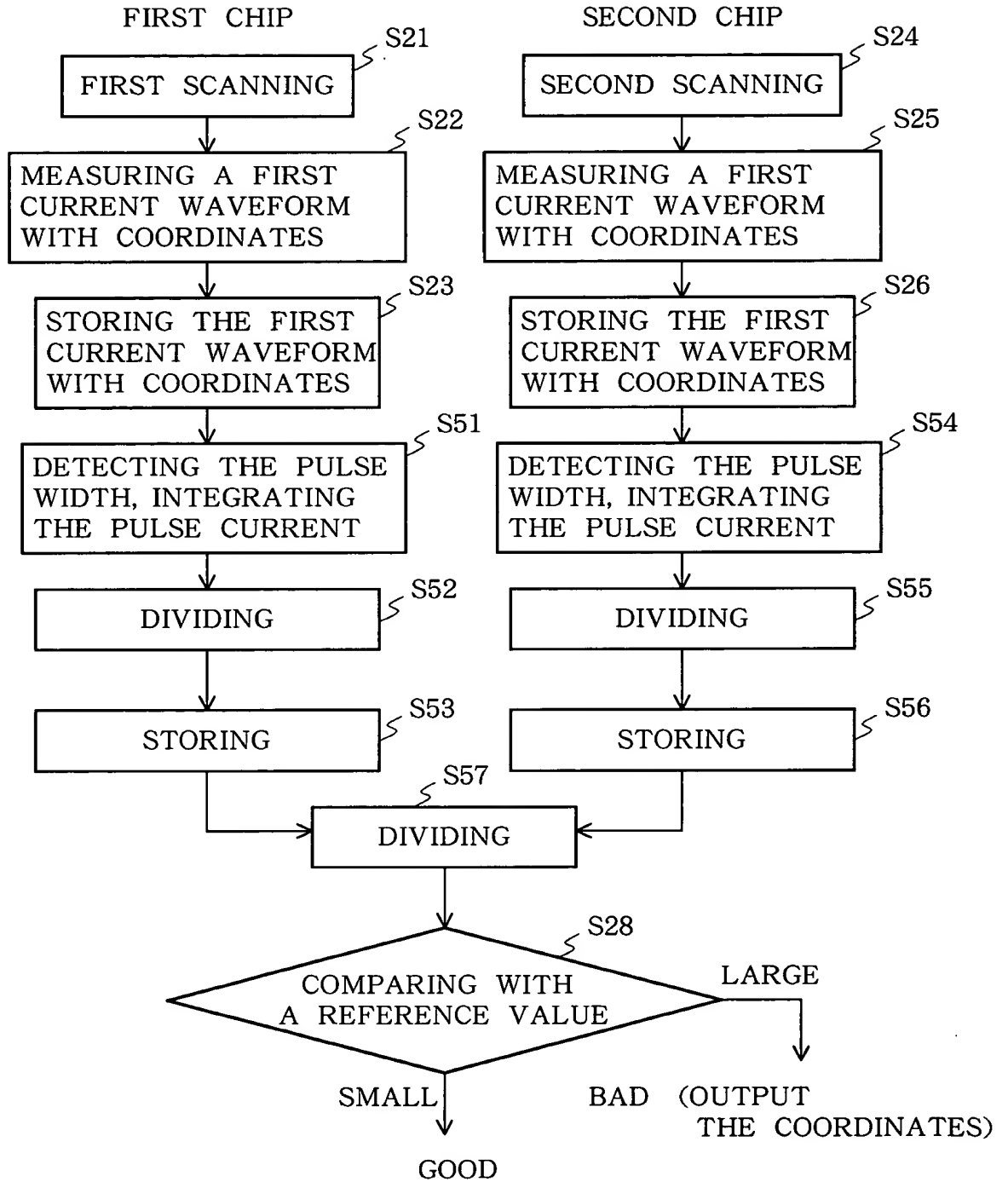


FIG.41

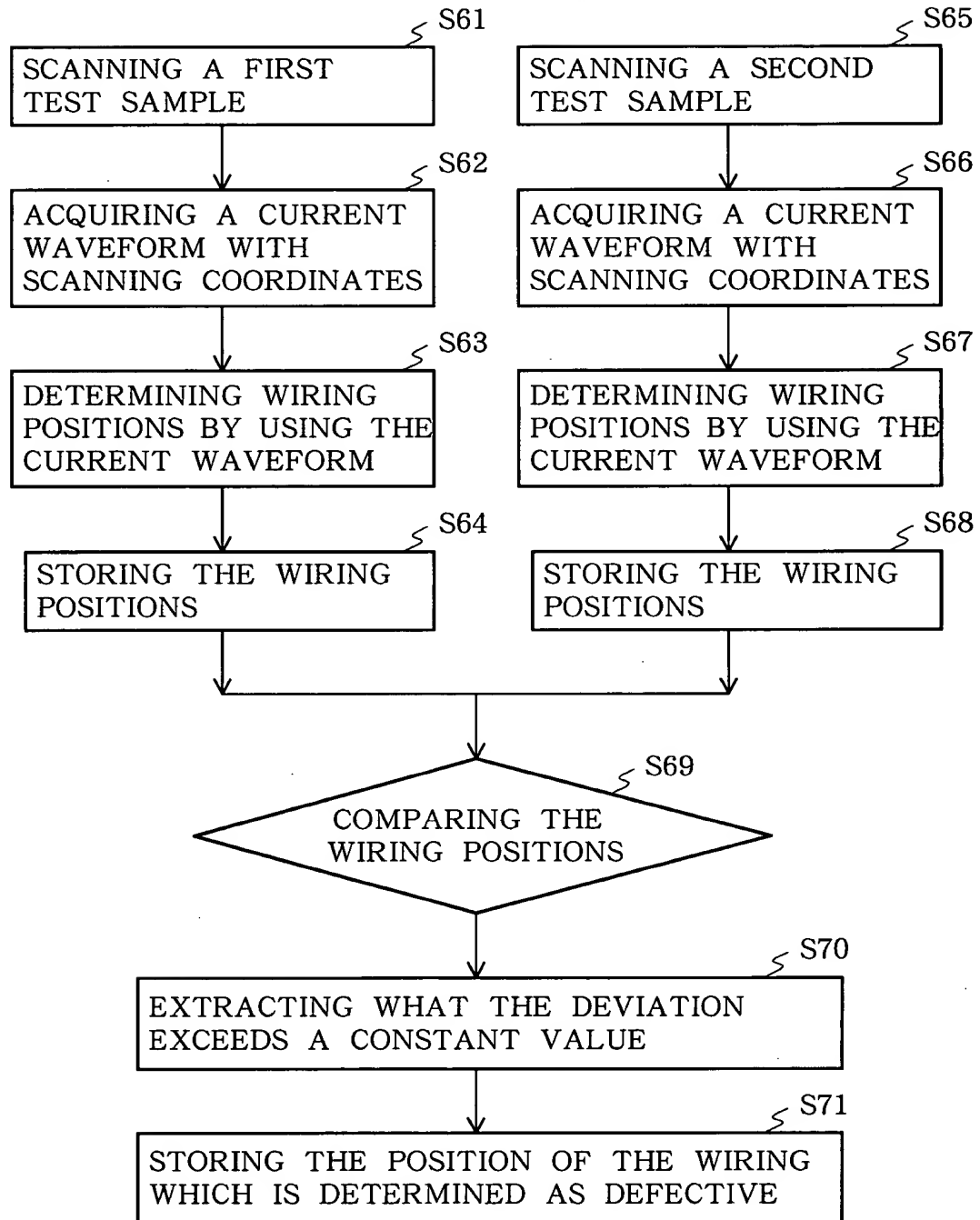


FIG.42

COMPENSATION  
CURRENT

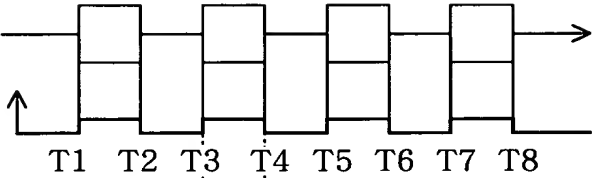
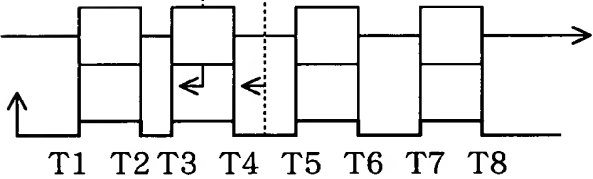


FIG.43a

COMPENSATION  
CURRENT



TIME

FIG.43b

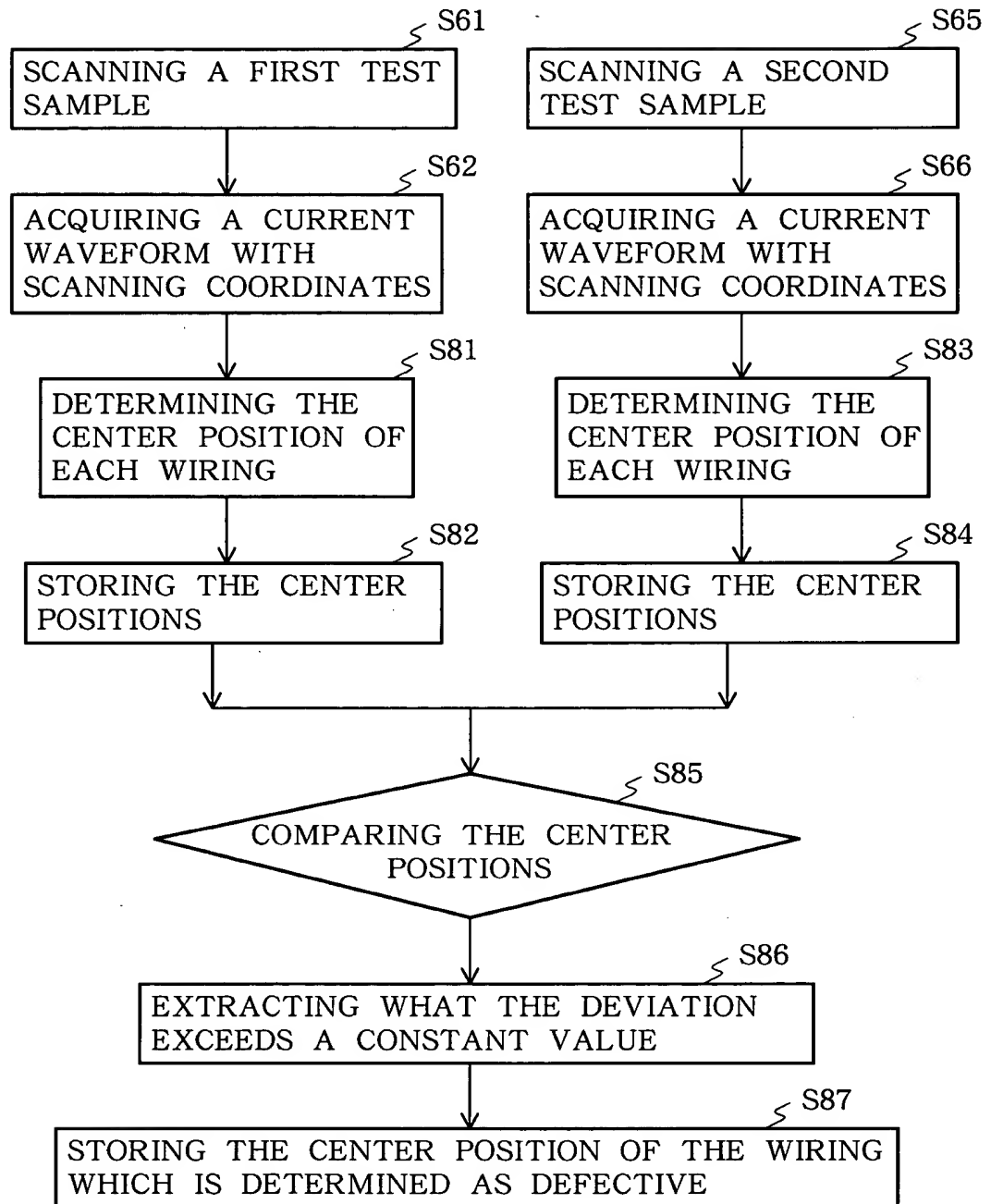


FIG.44

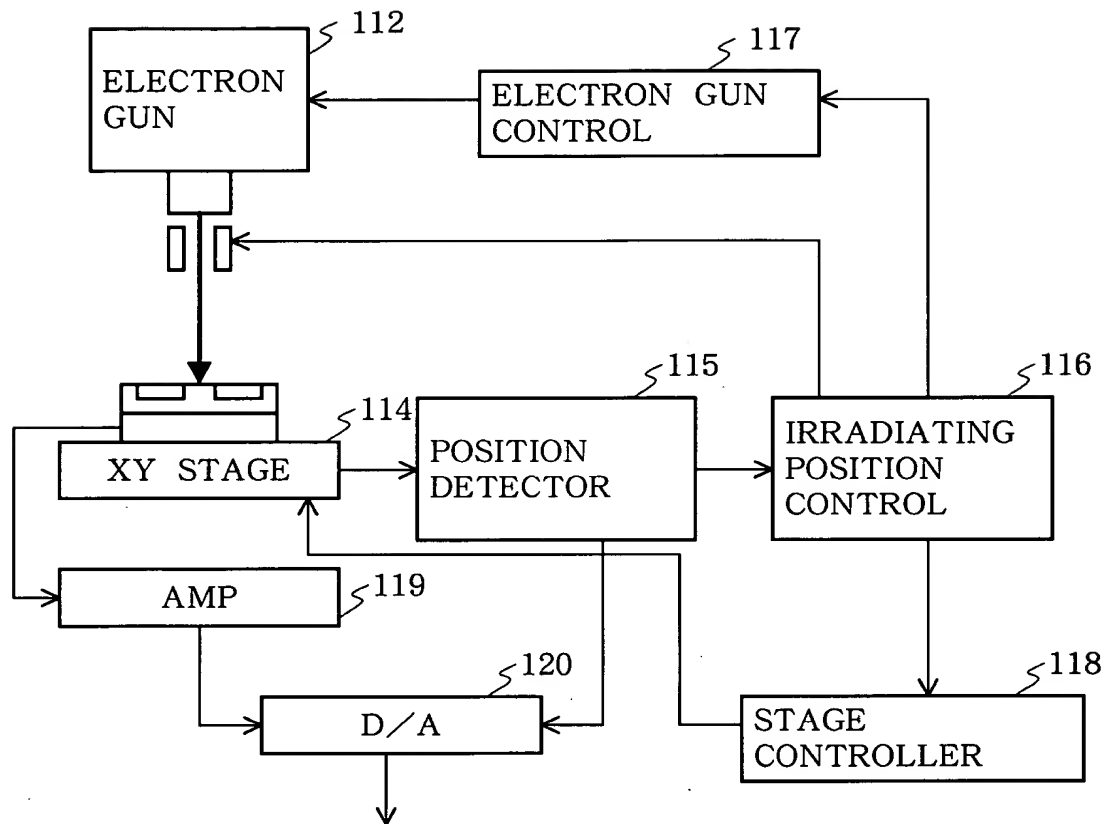


FIG.45





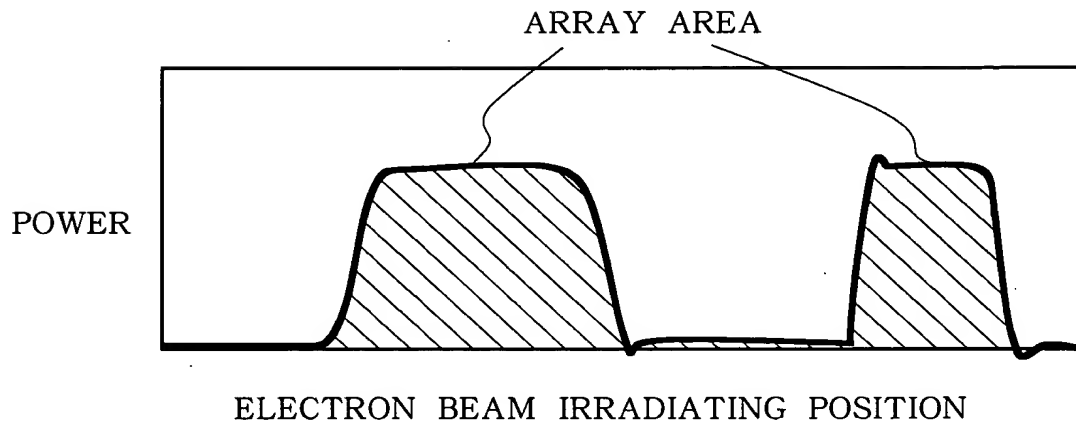


FIG.48

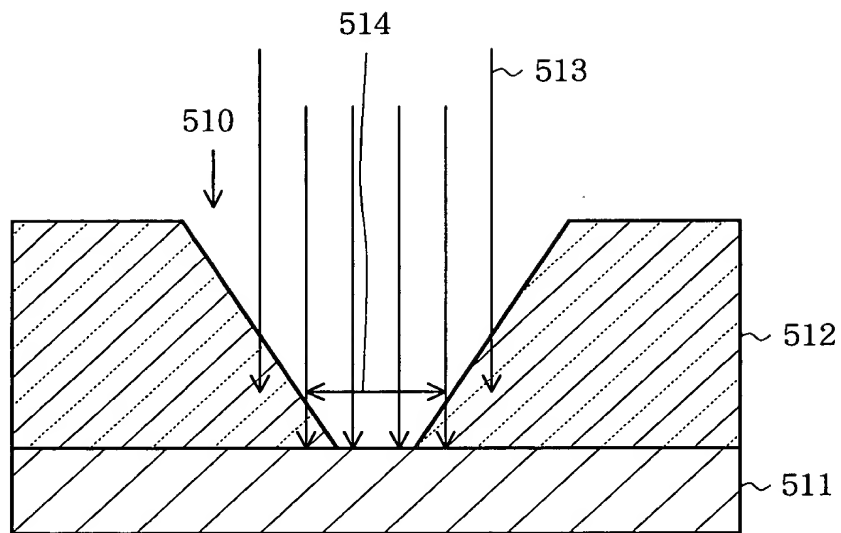


FIG.49

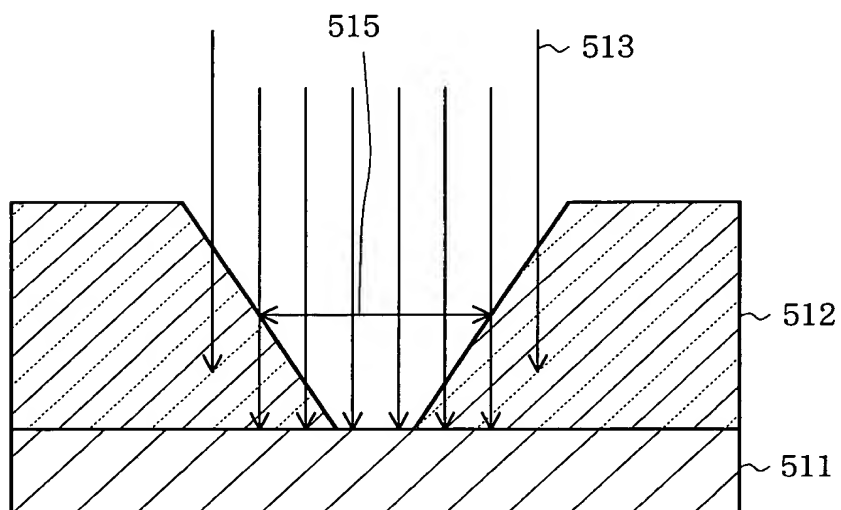


FIG.50

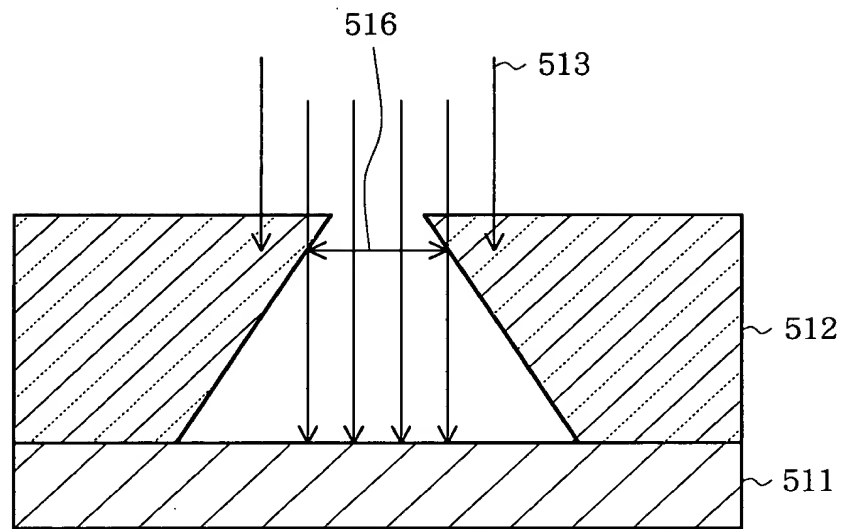


FIG.51

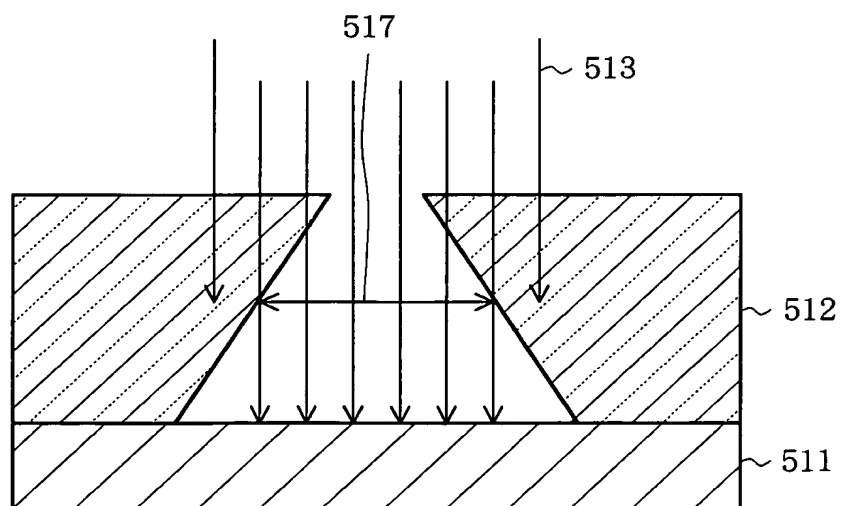


FIG.52

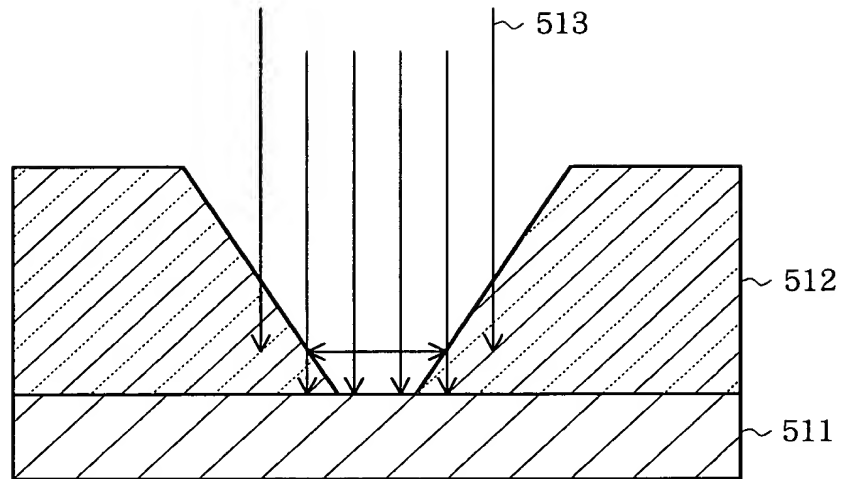


FIG. 53

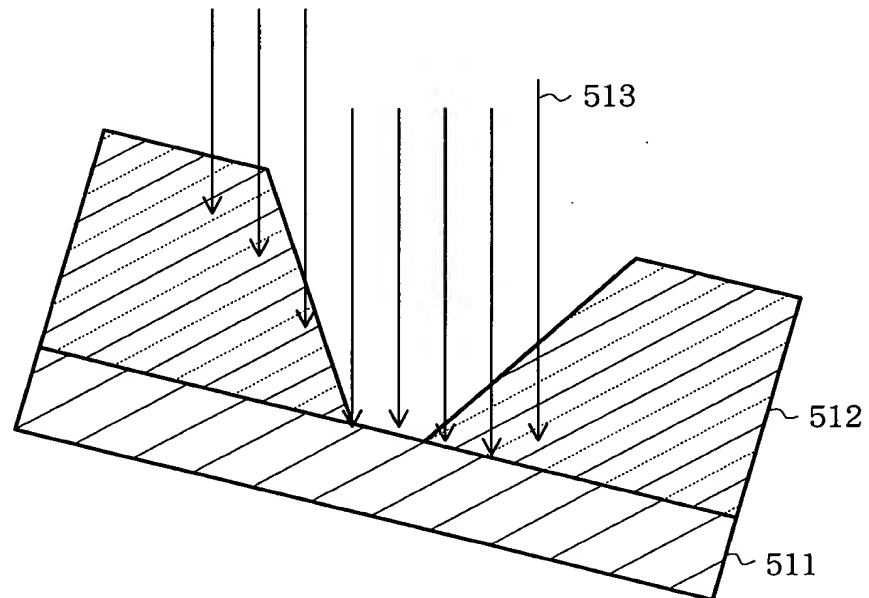


FIG. 54

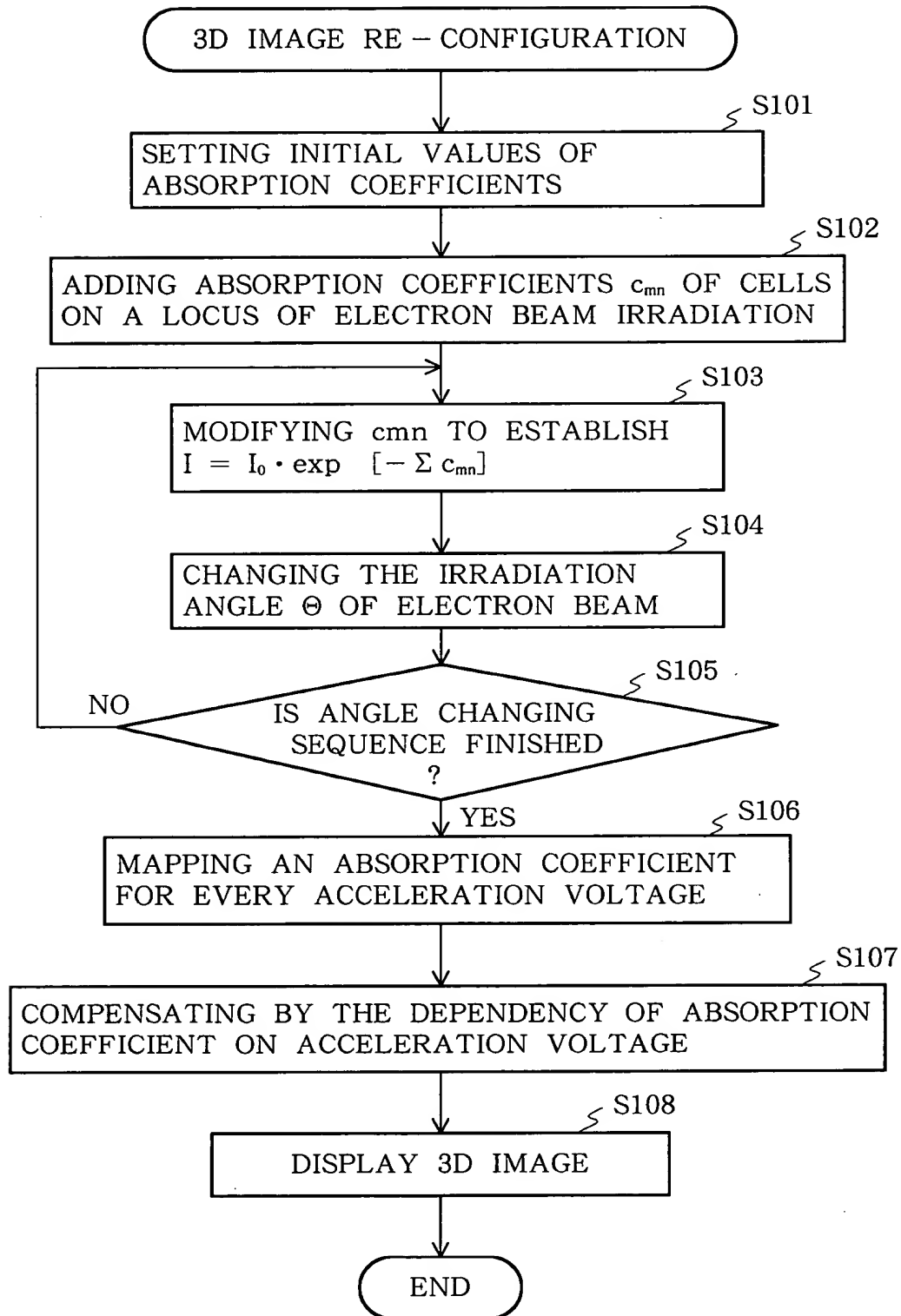


FIG.55

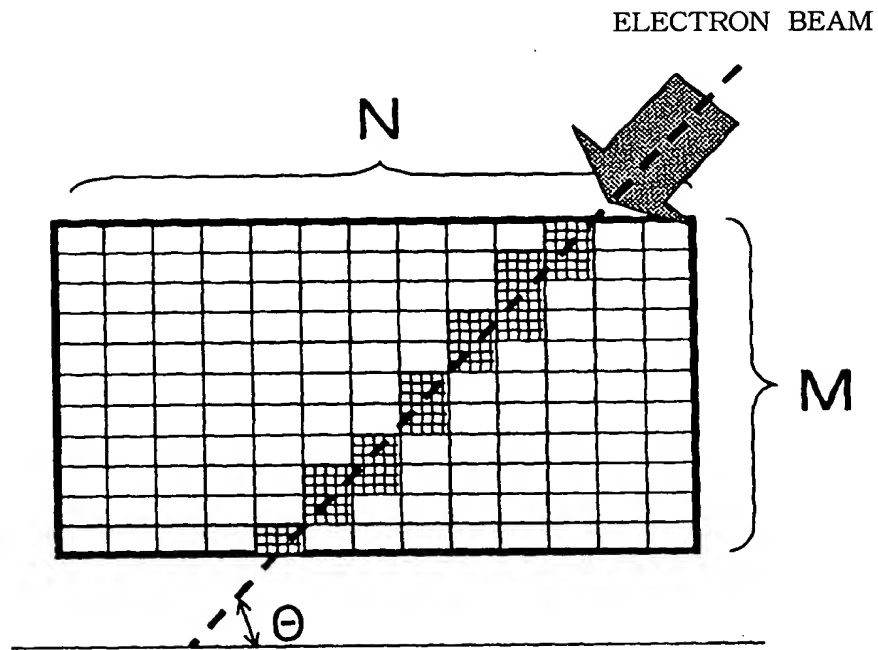


FIG.56

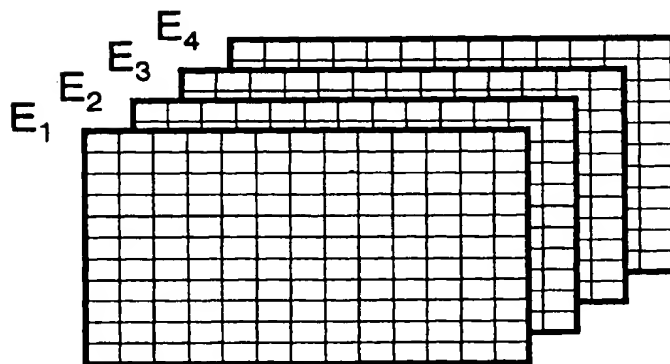
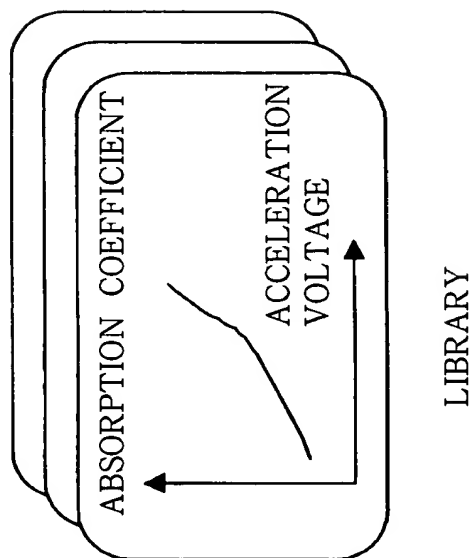
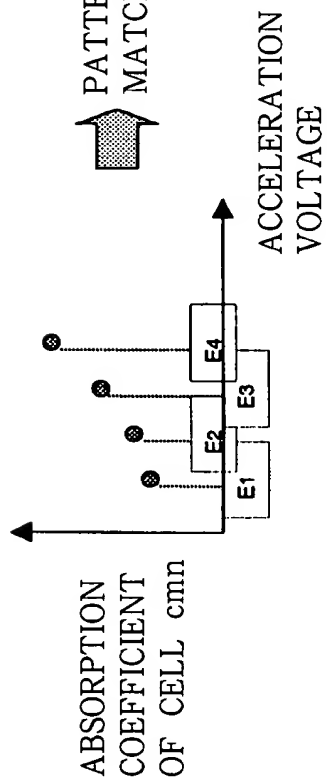


FIG.57



LIBRARY

PATTERN  
MATCHING



MEASURED DATA

FIG.58

FIG.59a

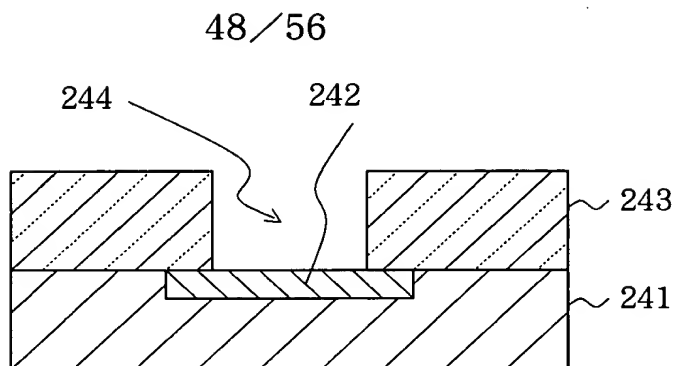


FIG.59b

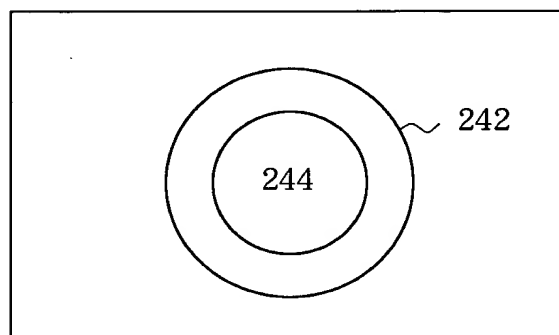


FIG.60a

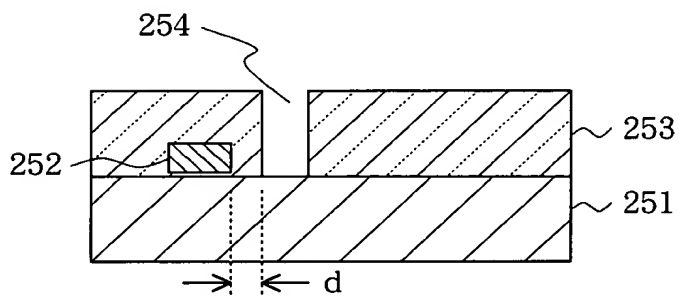


FIG.60b

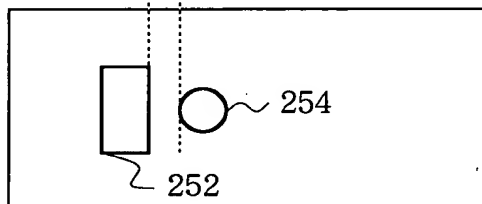




FIG.61a

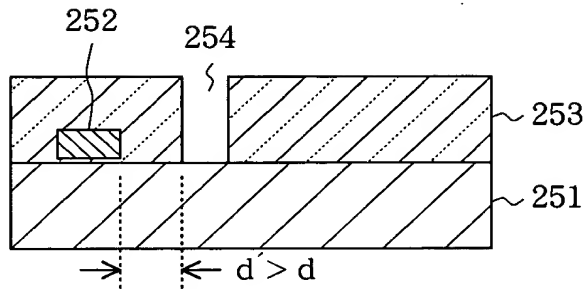


FIG.61b

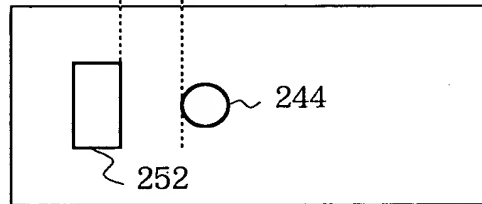


FIG.62a

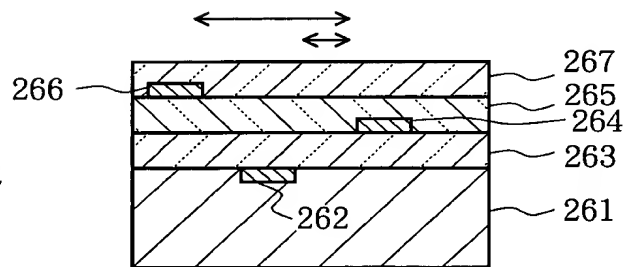
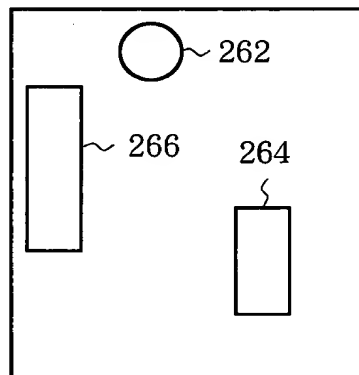


FIG.62b



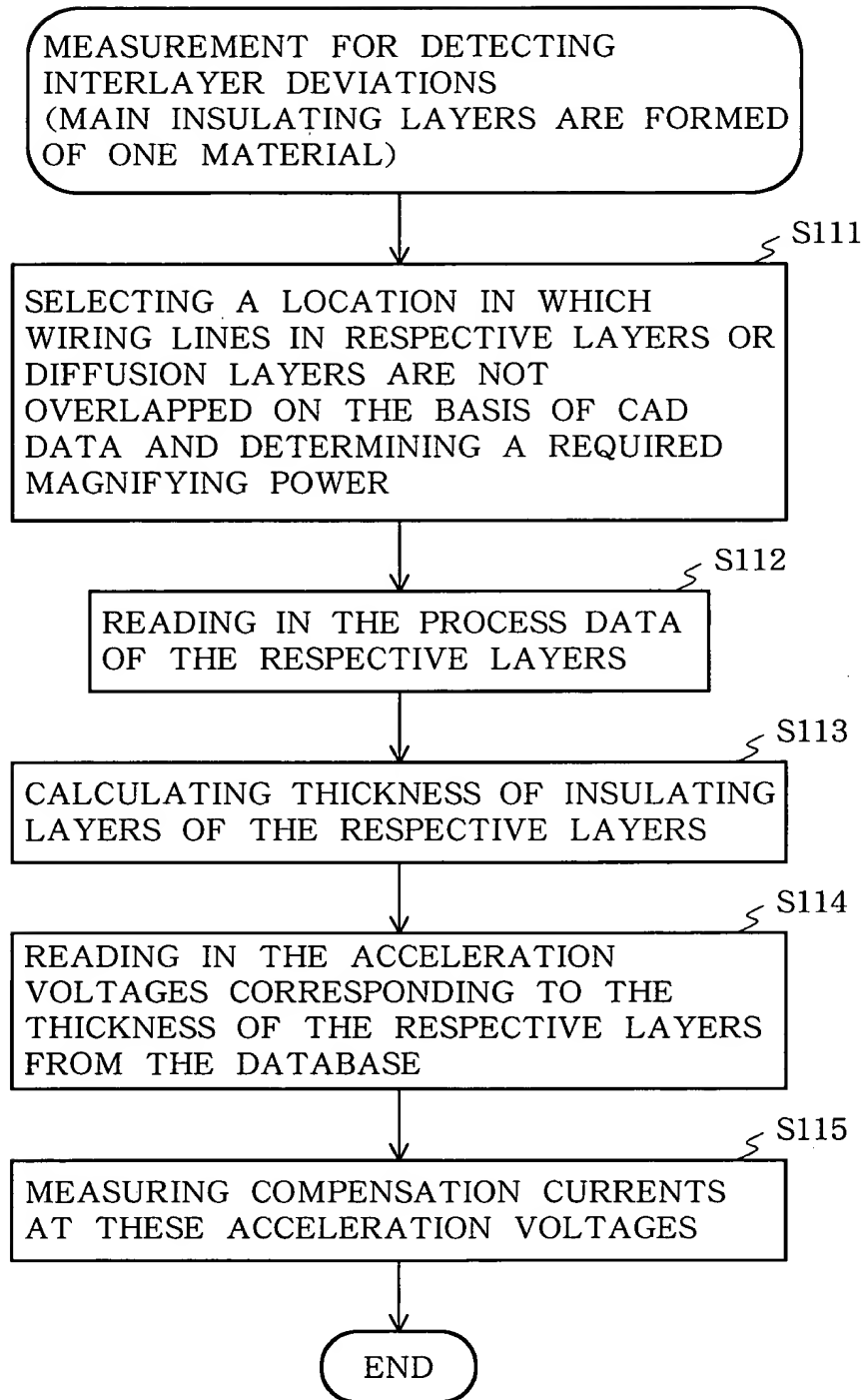


FIG.63

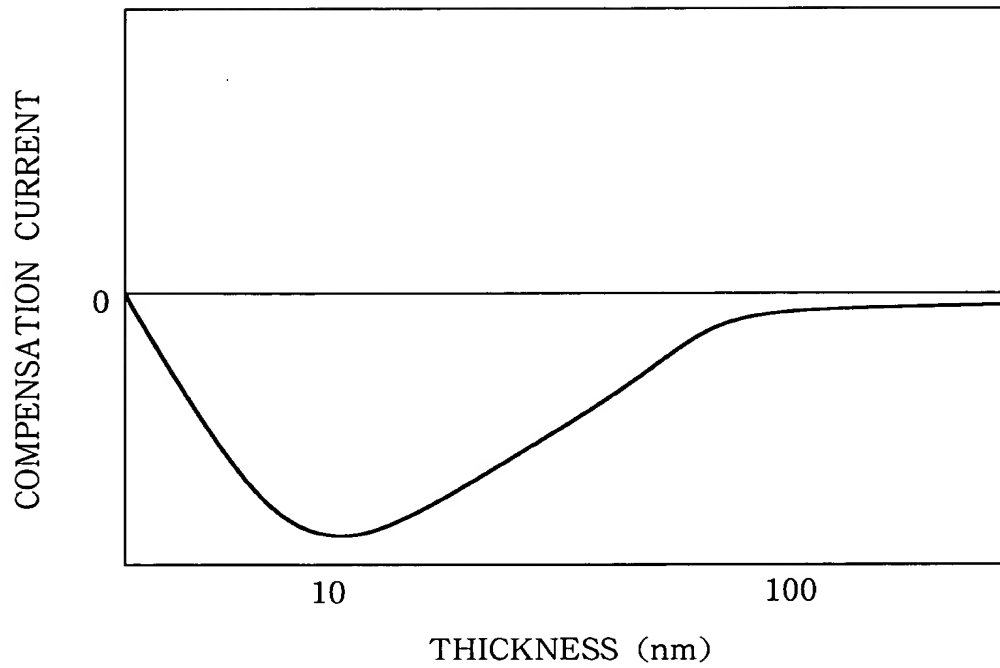


FIG.64

ON SUCH A POINT,  
IT IS CONSIDERED FOR  
ELECTRON BEAM TO PENETRATE

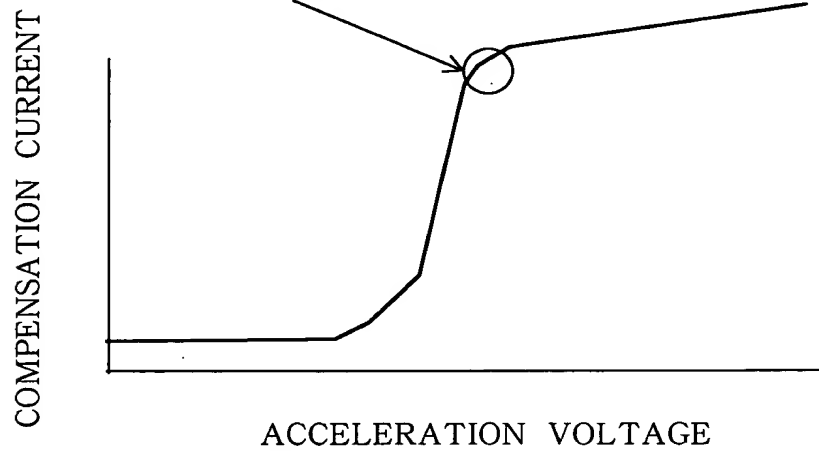


FIG.65

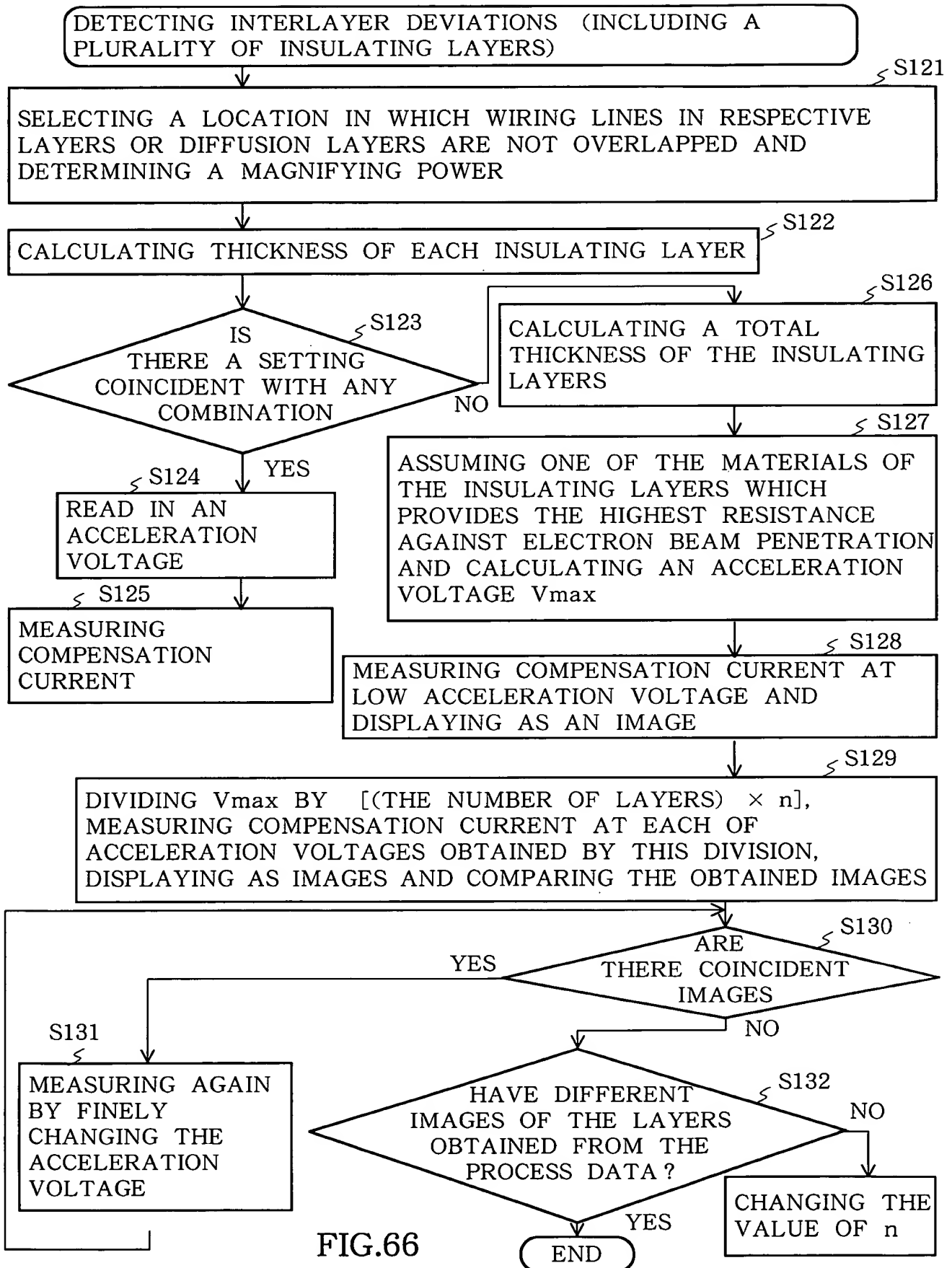


FIG.66

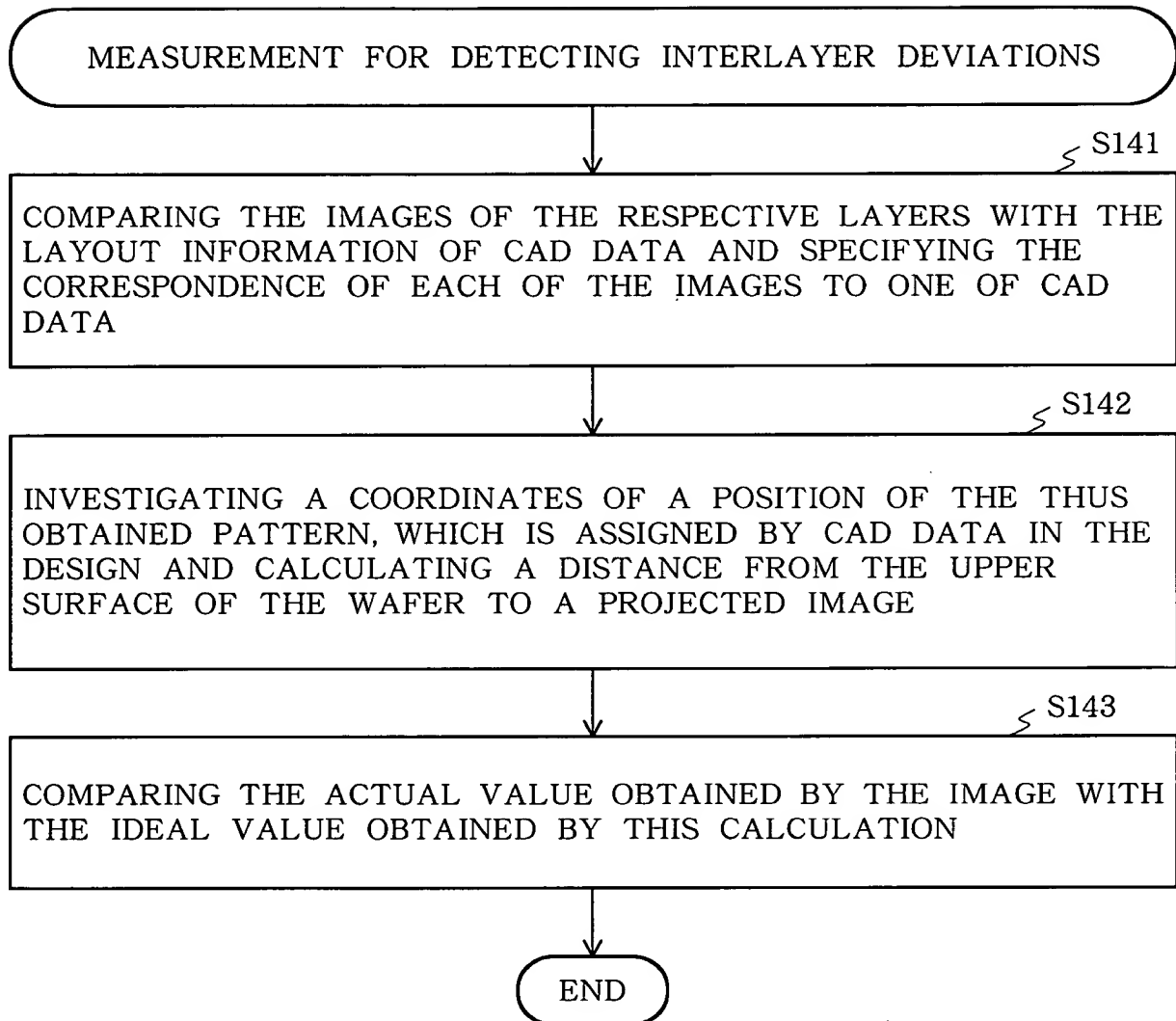


FIG.67

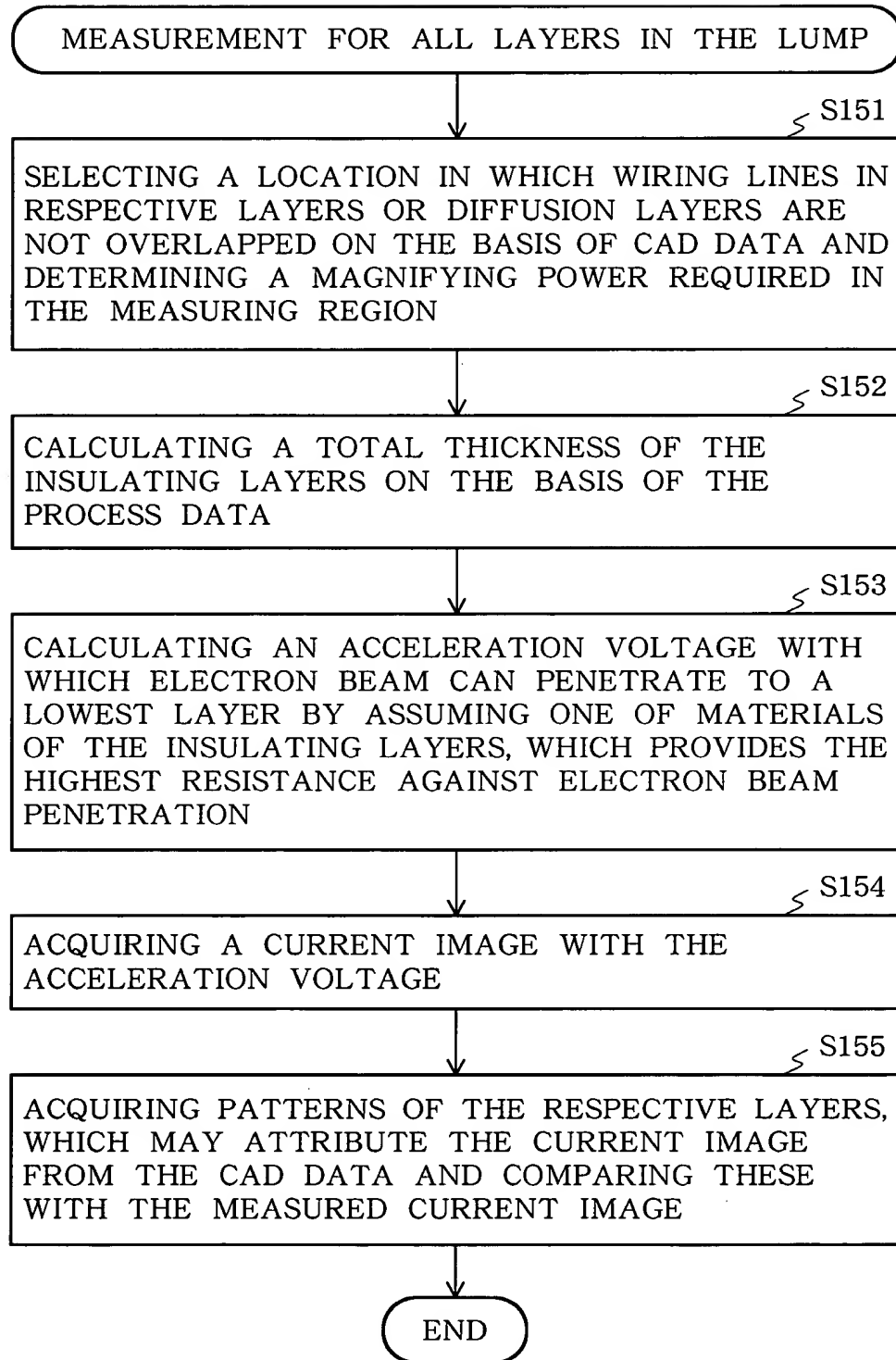


FIG.68

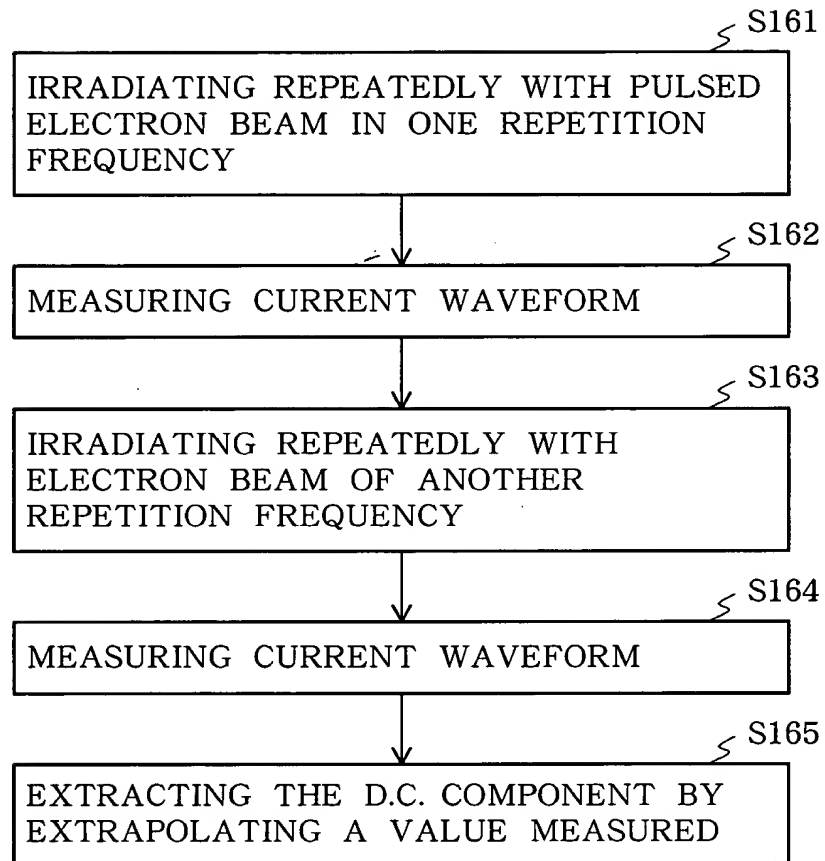


FIG.69

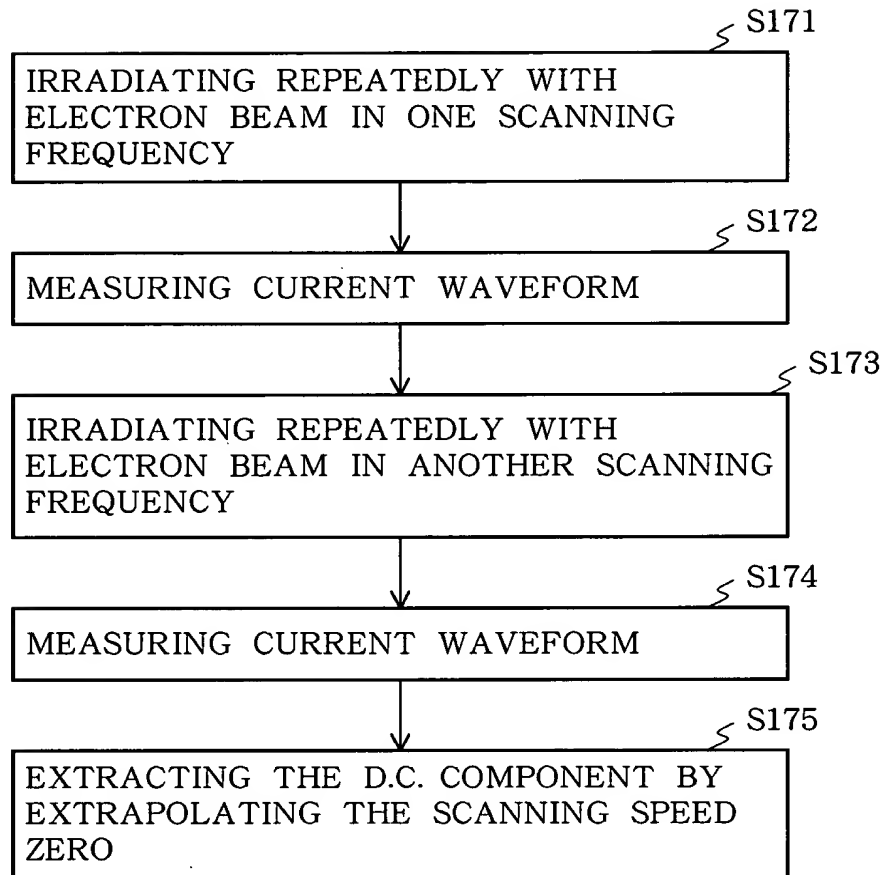


FIG.70